RL78/I1A

RENESAS MCU

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True Low Power Platform, High Resolution PWM and Rich Analog, 2.7 V to 5.5 V operation, 32 to 64 Kbyte Flash, for Inverter Control, Digital Power Control and Lighting Control Applications

1. OUTLINE

1.1 Features

Ultra-Low Power Technology
- 2.7 V to 5.5 V operation from a single supply
- Stop (RAM retained): 0.23 μA, (LVD enabled): 0.31 μA
- Halt (RTC + LVD): 0.60 μA
- Operating: 156.25 μA/MHz

16-bit RL78 CPU Core
- Delivers 41 DMIPS at maximum operating frequency of 32 MHz
- <R> Instruction execution: 86% of instructions can be executed in 1 to 2 clock cycles
- CISC architecture (Harvard) with 3-stage pipeline
- <R> Multiply signed & unsigned: 16 x 16 to 32-bit result in 1 clock cycle
- MAC: 16 x 16 to 32-bit result in 2 clock cycles
- 16-bit barrel shifter for shift & rotate in 1 clock cycle
- 1-wire on-chip debug function

Main Flash Memory
- Density: 32 KB to 64 KB
- Block size: 1 KB
- On-chip single voltage flash memory with protection from block erase/writing
- Self-programming with secure boot swap function and flash shield window function

Data Flash Memory
- Data flash with background operation
- Data flash size: 4 KB
- Erase cycles: 1 million (typ.)
- Erase/programming voltage: 2.7 V to 5.5 V

RAM
- 2 KB to 4 KB size options
- Supports operands or instructions
- Back-up retention in all modes

High-speed On-chip Oscillator
- 32 MHz with +/– 1% accuracy over voltage (2.7 V to 5.5 V) and temperature (–20°C to 85°C)
- Pre-configured settings: 32 MHz, 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz & 1 MHz

Reset and Supply Management
- Power-on reset (POR) monitor/generator
- Low voltage detection (LVD) with 6 setting options (Interrupt and/or reset function)

Data Memory Access (DMA) Controller
- Up to 2 fully programmable channels
- Transfer unit: 8- or 16-bit

16-bit timers KB0 to KB2, and KC0 for PWM output

16-bit timers KB0 to KB2: maximum 6 outputs (3 channels × 2)
- Smooth start function, dithering function, forced output stop function (unsynchronized with comparator or external interrupt) enables over-voltage protection, over-current protection and peak current control, and single/interleave PFC function
- Average resolution < 0.98 nsec output, 64 MHz (when using PLL) + dithering option

16-bit timer KC0 (1 channel × 6 (output))
- PWM output gating function by interlocking with 16-bit timers KB0, KB1, and KB2

Extended-Function Timers
- Multi-function 16-bit timers: Up to 8 channels
- Real-time clock (RTC): 1 channel (full calendar and alarm function with watch correction function)
- Interval timer: 12-bit, 1 channel
- 15 kHz watchdog timer: 1 channel (window function)

Multiple Communication Interfaces
- Up to 1 channel x I^2C multi-master (SMBus/PMBus support)
- Up to 1 channel x CSI/SPI (7-, 8-bit)
- Up to 3 channels x UART (7-, 8-, 9-bit), DALI support 1 channel (8-, 16-, 17-, 24-bit, master and slave)
- Up to 1 channel x LIN

Rich Analog
- ADC: Up to 11 channels, 8/10-bit resolution, 2.125 μs conversion time
- Supports 2.7 V
- Internal voltage reference (1.45 V)
- Comparator: High response time 70 ns (typ.), up to 6 channels, internal DAC 3 channels 8-bit resolution, window comparator mode
- PGA (x4 to x32): 6 input channels
- On-chip temperature sensor

Safety Features (IEC or UL 60730 compliance)
- Flash memory CRC calculation
- RAM parity error check
- RAM/SFR write protection
- Illegal memory access detection
- Clock stop/frequency detection
- ADC self-test

General Purpose I/O
- 5-V tolerant, high-current (up to 8.5 mA per pin)
- Open-drain, internal pull-up support

Operating Ambient Temperature
- Standard: –40°C to +105°C
- Extend: –40°C to +125°C

Package Type and Pin Count

SSOP: 20, 30, 38

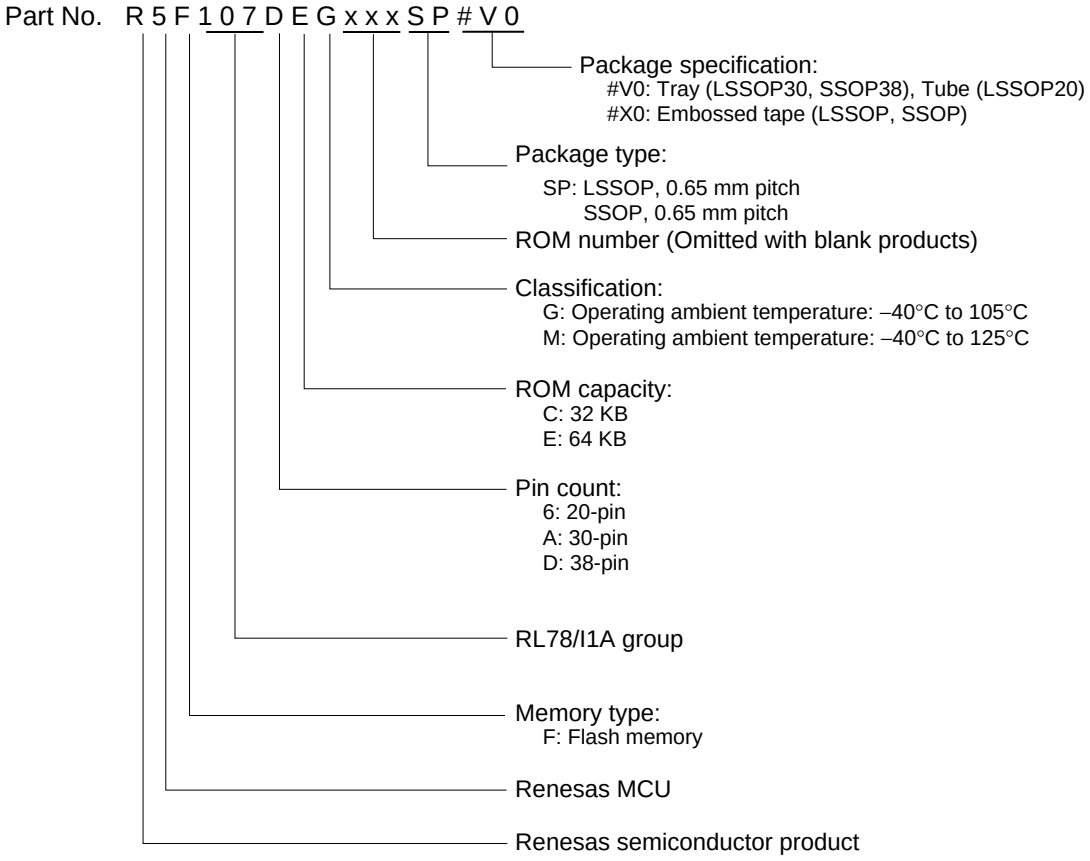
○ ROM, RAM capacities

Flash ROM	Data flash	RAM	RL78/I1A		
			20 pins	30 pins	38 pins
64 KB	4 KB	4 KB Note	–	R5F107AE	R5F107DE
32 KB	4 KB	2 KB	R5F1076C	R5F107AC	–

Note This is about 3 KB when the self-programming function and data flash function are used.

1.2 List of Part Numbers

Figure 1-1. Part Number, Memory Size, and Package of RL78/I1A



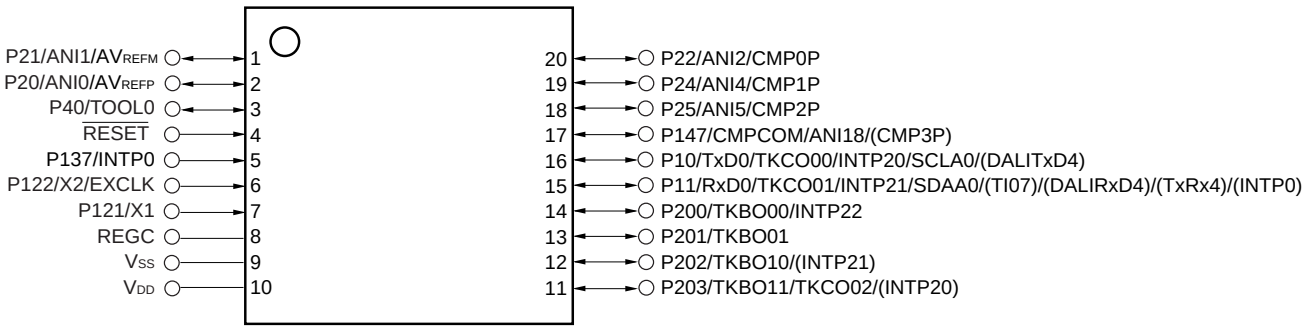
Pin count	Package	Operating Ambient Temperature	Part Number
20 pins	20-pin plastic LSSOP (4.4 × 6.5)	T_A = –40 to +105°C	R5F1076CGSP#V0, R5F1076CGSP#X0
		T_A = –40 to +125°C	R5F1076CMSP#V0, R5F1076CMSP#X0
30 pins	30-pin plastic LSSOP (7.62 mm (300))	T_A = –40 to +105°C	R5F107ACGSP#V0, R5F107AEGSP#V0, R5F107ACGSP#X0, R5F107AEGSP#X0
		T_A = –40 to +125°C	R5F107ACMSP#V0, R5F107AEMSP#V0, R5F107ACMSP#X0, R5F107AEMSP#X0
38 pins	38-pin plastic SSOP (7.62 mm (300))	T_A = –40 to +105°C	R5F107DEGSP#V0, R5F107DEGSP#X0
		T_A = –40 to +125°C	R5F107DEMSP#V0, R5F107DEMSP#X0

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.

1.3 Pin Configuration (Top View)

1.3.1 20-pin products

- 20-pin plastic LSSOP (4.4 x 6.5)



Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μF).

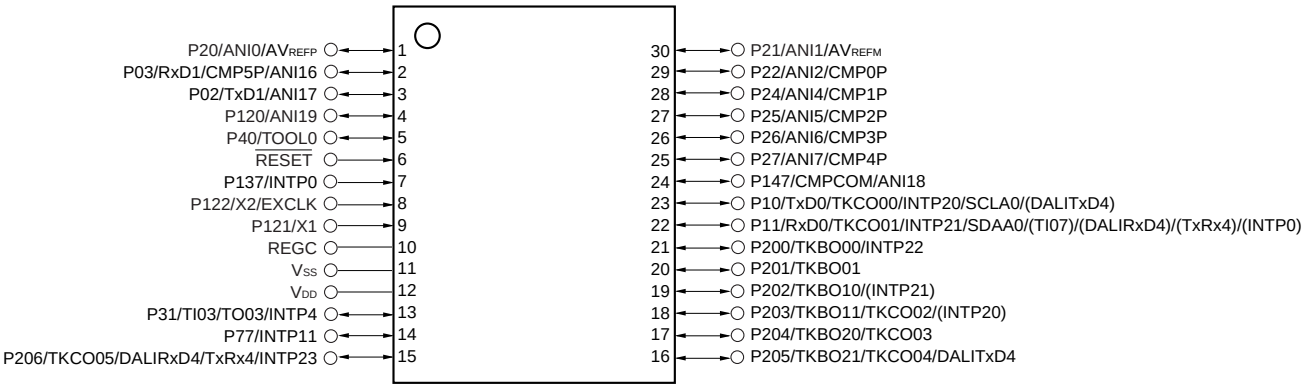
Remarks 1. For pin identification, see **1.4 Pin Identification**.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR1) or the input switch control register (ISC). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR1)** and **Figure 15-20 Format of Input Switch Control Register (ISC) in the RL78/I1A User's Manual**.

3. The shared function CMP3P can be assigned to P147 by setting the CMPSEL0 bit in the comparator input switch control register (CMPSEL).

1.3.2 30-pin products

- 30-pin plastic LSSOP (7.62 mm (300))



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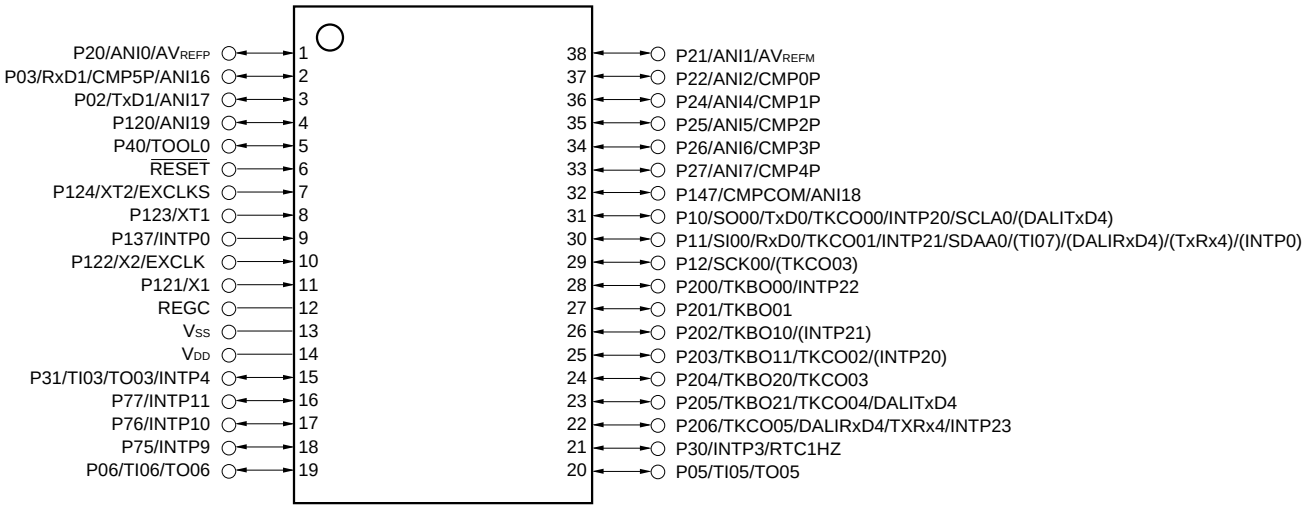
Remarks 1. For pin identification, see **1.4 Pin Identification**.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR1) or the input switch control register (ISC). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR1)** and **Figure 15-20 Format of Input Switch Control Register (ISC) in the RL78/I1A User's Manual**.

1.3.3 38-pin products

- 38-pin plastic SSOP (7.62 mm (300))



Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μF).

Remarks 1. For pin identification, see **1.4 Pin Identification**.

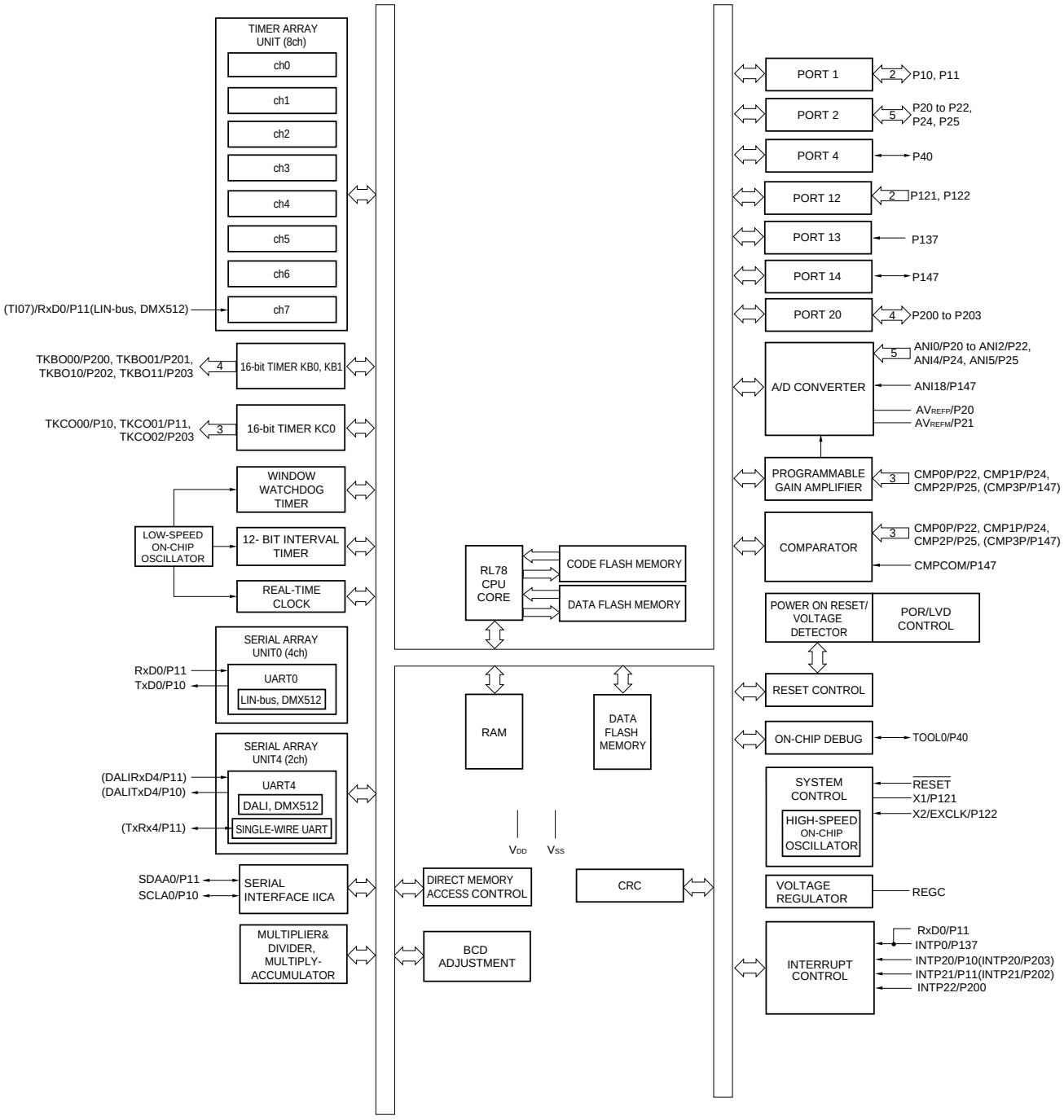
2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR1) or the input switch control register (ISC). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR1)** and **Figure 15-20 Format of Input Switch Control Register (ISC) in the RL78/I1A User's Manual**.

1.4 Pin Identification

ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19:	Analog Input
AV_{REFM}:	Analog Reference Voltage Minus
AV_{REFP}:	Analog Reference Voltage Plus
CMP0P to CMP5P:	Comparator Analog Input
CMPCOM:	Comparator External Reference Voltage
EXCLK:	External Clock Input (Main System Clock)
EXCLKS:	External Clock Input (Subsystem Clock)
INTP0, INTP3, INTP4, INTP9, INTP10, INTP11, INTP20 to INTP23:	Interrupt Request from Peripheral
P02, P03, P05, P06:	Port 0
P10 to P12:	Port 1
P20 to P22, P24 to P27:	Port 2
P30, P31:	Port 3
P40:	Port 4
P75 to P77:	Port 7
P120 to P124:	Port 12
P137:	Port 13
P147:	Port 14
P200 to P206:	Port 20
REGC:	Regulator Capacitance
RESET:	Reset
RTC1HZ:	Real-time Clock Correction Clock (1 Hz) Output
RxD0, RxD1, DALIRxD4:	Receive Data
SCK00:	Serial Clock Input/Output
SCLA0:	Serial Clock Input/Output
SDAA0:	Serial Data Input/Output
SI00:	Serial Data Input
SO00:	Serial Data Output
TI03, TI05, TI06, TI07:	Timer Input
TO03, TO05, TO06, TKBO00, TKBO01 to TKBO20, TKBO21, TKCO00 to TKCO05:	Timer Output
TOOL0:	Data Input/Output for Tool
TxRx4:	Serial Data Input/Output for Single Wired UART
TxD0, TxD1 DALITxD4:	Transmit Data
V_{DD}:	Power Supply
V_{SS}:	Ground
X1, X2:	Crystal Oscillator (Main System Clock)
XT1, XT2:	Crystal Oscillator (Subsystem Clock)

1.5 Block Diagram

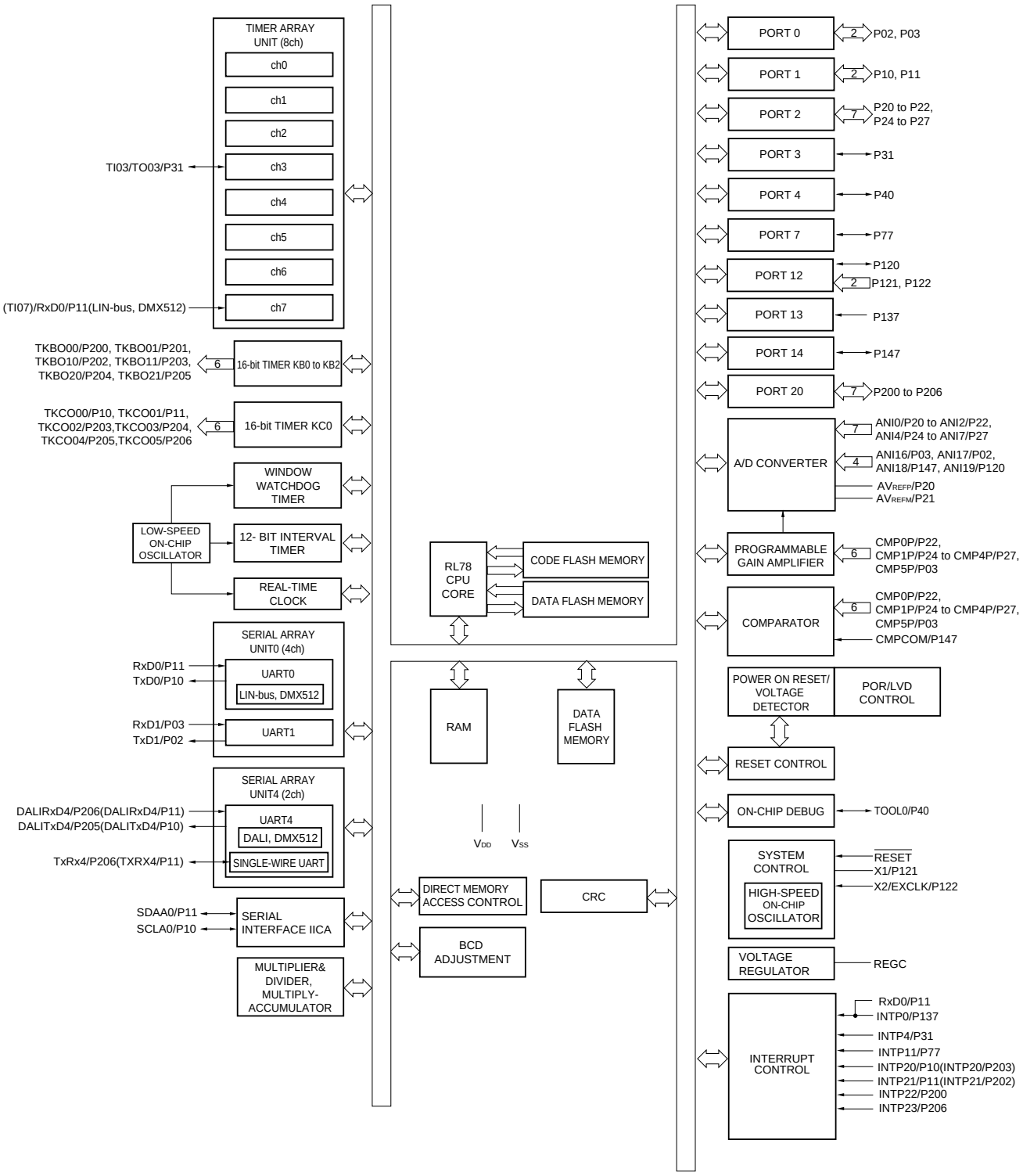
1.5.1 20-pin products



Remarks 1. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR1) or the input switch control register (ISC). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR1)** and **Figure 15-20 Format of Input Switch Control Register (ISC) in the RL78/I1A User's Manual**.

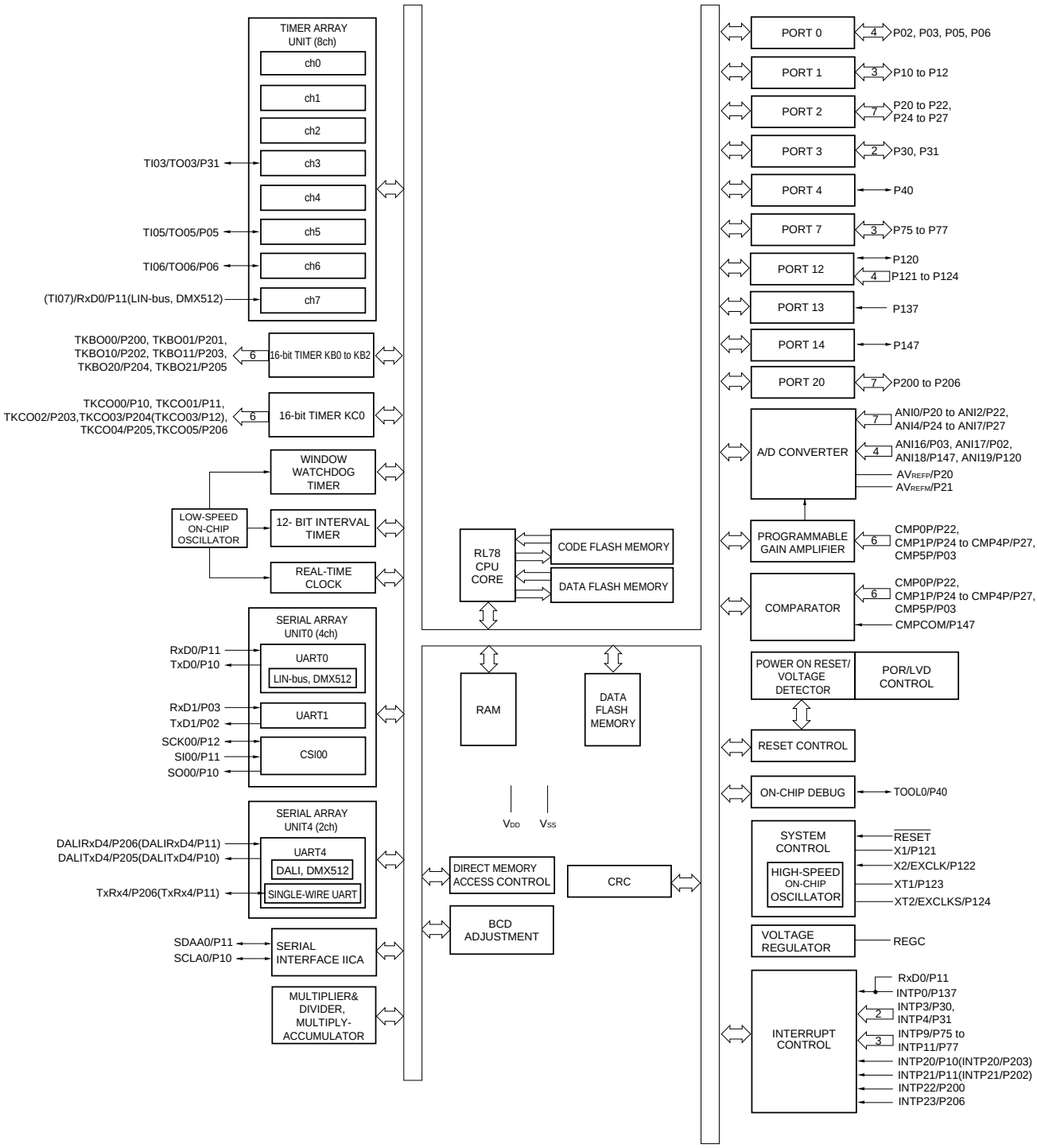
2. The shared function CMP3P can be assigned to P147 by setting the CMPSEL0 bit in the comparator input switch control register (CMPSEL).

1.5.2 30-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR1) or the input switch control register (ISC). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR1)** and **Figure 15-20 Format of Input Switch Control Register (ISC) in the RL78/I1A User's Manual**.

1.5.3 38-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR1) or the input switch control register (ISC). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR1)** and **Figure 15-20 Format of Input Switch Control Register (ISC) in the RL78/I1A User's Manual**.

1.6 Outline of Functions

Caution This outline describes the functions at the time when Peripheral I/O redirection register (PIOR1) is set to 00H.

(1/3)

Item		20-pin	30-pin		38-pin
		R5F1076C	R5F107AC	R5F107AE	R5F107DE
Code flash memory (KB)		32	32	64	64
Data flash memory (KB)		4	4	4	4
RAM (KB)		2	2	4Note 1	4Note 1
Address space		1 MB			
Main system clock	High-speed system clock	X1 (crystal/ceramic) oscillation, external main system clock input (EXCLK) HS (High-speed main) mode: 1 to 20 MHz (V_{DD} = 2.7 to 5.5 V), LS (Low-speed main) mode: 1 to 8 MHz (V_{DD} = 2.7 to 5.5 V)			
	High-speed on-chip oscillator	HS (High-speed main) mode: 1 to 32 MHz (V_{DD} = 2.7 to 5.5 V), LS (Low-speed main) mode: 1 to 8 MHz (V_{DD} = 2.7 to 5.5 V)			
Clock for 16-bit timers KB0 to KB2, and KC0		64 MHz (TYP.)			
Subsystem clock (38-pin products only)		XT1 (crystal) oscillation, external subsystem clock input (EXCLKS) 32.768 kHz			
Low-speed on-chip oscillator		15 kHz (TYP.)			
General-purpose register		(8-bit register × 8) × 4 banks			
Minimum instruction execution time		0.03125 μs (High-speed on-chip oscillator: f_{IH} = 32 MHz operation)			
		0.05 μs (High-speed system clock: f_{MX} = 20 MHz operation)			
		30.5 μs (Subsystem clock: f_{SUB} = 32.768 kHz operation) (38-pin products only)			
Instruction set		• 8-bit operation, 16-bit operation • Multiplication (8 bits × 8 bits) • Bit manipulation (Set, reset, test, and Boolean operation), etc.			
I/O port	Total	16	26		34
	CMOS I/O	13	23		29
	CMOS input	3	3		5
	CMOS output	–	–		–
Timer	16-bit timer TAU	8 channels (no timer output)	8 channels (timer output: 1, PWM output: 1Note 2)		8 channels (timer outputs: 3, PWM outputs: 3Note 2)
	16-bit timer KB	2 channels (PWM outputs: 4)	3 channels (PWM outputs: 6)		
	16-bit timer KC	1 channel (PWM outputs: 3)	1 channel (PWM outputs: 6)		

Notes 1. This is about 3 KB when the self-programming function and data flash function are used. (For details, see **CHAPTER 3 in the RL78/I1A User's Manual**.)

2. The number of PWM outputs varies depending on the setting of channels in use (the number of masters and slaves) (see **6.9.3 Operation as multiple PWM output function in the RL78/I1A User's Manual**).

(2/3)

Item			20-pin	30-pin	38-pin
			R5F1076C	R5F107AC, R5F107AE	R5F107DE
Timer	Watchdog timer		1 channel		
	Real-time clock (RTC)		1 channel[Notes 1, 2]		
	12-bit interval timer (IT)		1 channel		
	RTC output		–		1 1 Hz (subsystem clock: f_{SUB} = 32.768 kHz)
8/10-bit resolution A/D converter			6 channels	11 channels	11 channels
Comparator			4 channels	6 channels	6 channels
Programmable gain amplifier			1 channel		
		Input[Note 3]	4 channels	6 channels	6 channels
Serial interface			[20-pin] [Note 5] • UART (Supporting LIN-bus and DMX512): 1 channel • UART (Supporting DALI communication): 1 channel [30-pin products] • UART (Supporting LIN-bus and DMX512): 1 channel • UART: 1 channel • UART (Supporting DALI communication): 1 channel [38-pin products] • CSI: 1 channel/UART (Supporting LIN-bus and DMX512): 1 channel • UART: 1 channel • UART (Supporting DALI communication): 1 channel		
	I^2C bus		1 channel	1 channel	1 channel
Multiplier and divider/multiply-accumulator			• 16 bits × 16 bits = 32 bits (Unsigned or signed) • 32 bits ÷ 32 bits = 32 bits (Unsigned) • 16 bits × 16 bits + 32 bits = 32 bits (Unsigned or signed)		
DMA controller			2 channels		
Vectored interrupt sources	Internal		27	30	30
	External		7	10	11
Reset			• Reset by $\overline{\text{RESET}}$ pin • Internal reset by watchdog timer • Internal reset by power-on-reset • Internal reset by voltage detector • Internal reset by illegal instruction execution[Note 4] • Internal reset by RAM parity error • Internal reset by illegal-memory access		

Notes 1. The subsystem clock (f_{SUB}) can be selected as the operating clock only for 38-pin products.

2. The 20- and 30-pin products can only be used as the constant-period interrupt function.

3. The comparator input is alternatively used with analog input pin (ANI pin).

4. The illegal instruction is generated when instruction code FFH is executed.
Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

5. The 20 pin products can only be used 1 UART simultaneously due to sharing of the same I/O pins.

(3/3)

Item	20-pin	30-pin	38-pin
	R5F1076C	R5F107AC, R5F107AE	R5F107DE
Power-on-reset circuit	• Power-on-reset: 1.51 V (TYP.) • Power-down-reset: 1.50 V (TYP.)		
Voltage detector	• Rising edge: 2.81 V to 4.06 V (6 stages) • Falling edge: 2.75 V to 3.98 V (6 stages)		
On-chip debug function	Provided		
Power supply voltage	V_{DD} = 2.7 to 5.5 V		
Operating ambient temperature	T_A = –40 to +105°C (G: Industrial applications), T_A = –40 to +125°C (M: Industrial applications)		

2. ELECTRICAL SPECIFICATIONS (G: Industrial applications, T_A = –40 to +105°C)

In this chapter, shows the electrical specifications of the target products.

Target products (G: Industrial applications): T_A = – 40 to + 105°C
R5F107xxGxx

Cautions 1. The RL78/I1A has an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.

2. The pins mounted depend on the product. See 2.1 Port Function to 2.2.1 Functions for each product in the RL78/I1A User's Manual.

2.1 Absolute Maximum Ratings

Absolute Maximum Ratings (T_A = 25°C) (1/2)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V_{DD}		–0.5 to +6.5	V
REGC pin input voltage	V_{IREGC}	REGC	–0.3 to +2.8 and –0.3 to V_{DD} +0.3 Note 1	V
Input voltage	V_{I1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120 to P124, P137, P147, P200 to P206, EXCLK, EXCLKS, $\overline{\text{RESET}}$	–0.3 to V_{DD} +0.3 Note 2	V
Output voltage	V_{O1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	–0.3 to V_{DD} +0.3 Note 2	V
Analog input voltage	V_{AI1}	ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19	–0.3 to V_{DD} +0.3 and –0.3 to $AV_{REF(+)}$ +0.3 Notes 2, 3	V

Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μF). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

2. Must be 6.5 V or lower.

3. Do not exceed $AV_{REF(+)}$ + 0.3 V in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remarks 1. Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

2. $AV_{REF(+)}$: + side reference voltage of the A/D converter.

3. V_{SS}: Reference voltage

Absolute Maximum Ratings (T_A = 25°C) (2/2)

Parameter	Symbols	Conditions		Ratings	Unit
Output current, high	I_{OH1}	Per pin	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	–40	mA
		Total of all pins –170 mA	P02, P03, P40, P120	–70	mA
			P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206	–100	mA
	I_{OH2}	Per pin	P20 to P22, P24 to P27	–0.5	mA
		Total of all pins		–2	mA
Output current, low	I_{OL1}	Per pin	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	40	mA
		Total of all pins 170 mA	P02, P03, P40, P120	70	mA
			P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206	100	mA
	I_{OL2}	Per pin	P20 to P22, P24 to P27	1	mA
		Total of all pins		5	mA
Operating ambient temperature	T_A	In normal operation mode		–40 to +105	°C
		In flash memory programming mode			
Storage temperature	T_{stg}			–65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

2.2 Oscillator Characteristics

2.2.1 X1, XT1 oscillator characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation frequency (f_X)Note	Ceramic resonator/crystal resonator		1.0		20.0	MHz
XT1 clock oscillation frequency (f_{XT})Note	Crystal resonator		32	32.768	35	kHz

Note Indicates only permissible oscillator frequency ranges. See **AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

Remark When using the X1 oscillator and XT1 oscillator, see **5.4 System Clock Oscillator in the RL78/I1A User's Manual.**

2.2.2 On-chip oscillator characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Oscillators	Parameters	Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency[Note 1]	f_{IH}		1		32	MHz
High-speed on-chip oscillator clock frequency accuracy[Note 2]		T_A = –20 to 85°C	–1		+1	%
		T_A = –40 to 105°C	–1.5		+1.5	%
Low-speed on-chip oscillator clock frequency	f_{IL}			15		kHz
Low-speed on-chip oscillator clock frequency accuracy			–15		+15	%

Notes 1. Frequency can be selected in a high-speed on-chip oscillator. Selected by bits 0 to 3 of option byte (000C2H/010C2H).

2. This indicates the oscillator characteristics only. See **AC Characteristics** for instruction execution time.

2.2.3 PLL characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
PLL input clock frequency[Note]	f_{PLLIN}	High-speed system clock is selected (f_{MX} = 4 MHz)	3.94	4.00	4.06	MHz
		High-speed on-chip oscillator clock is selected (f_{IH} = 4 MHz)	3.94	4.00	4.06	MHz
PLL output clock frequency[Note]	f_{PLL}		f_{PLLIN} × 16			MHz

Note This only indicates the oscillator characteristics. See **AC Characteristics** for instruction execution time.

2.3 DC Characteristics

2.3.1 Pin characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high[Note 1]	I_{OH1}	Per pin for P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V			–3.0[Note 2]	mA
			2.7 V ≤ V_{DD} < 4.0 V			–1.0	mA
		Total of P02, P03, P40, P120 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			–12.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			–4.0	mA
		Total of P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			–30.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			–10.0	mA
		Total of all pins (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			–30.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			–14.0	mA
	I_{OH2}	Per pin for P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V			–0.1[Note 2]	mA
		Total of all pins (When duty ≤ 70%[Note 3])	2.7 V ≤ V_{DD} ≤ 5.5 V			–0.7	mA

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from the V_{DD} pin to an output pin.

2. However, do not exceed the total current value.

3. Specification under conditions where the duty factor ≤ 70%.
The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (I_{OH} × 0.7)/(n × 0.01)

<Example> Where n = 80% and I_{OH} = –10.0 mA

Total output current of pins = (–10.0 × 0.7)/(80 × 0.01) ≅ –8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P02, P10 to P12 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low[Note 1]	I_{OL1}	Per pin for P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V			8.5[Note 2]	mA
			2.7 V ≤ V_{DD} < 4.0 V			1.5[Note 2]	mA
		Total of P02, P03, P40, P120 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			40.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			7.5	mA
		Total of P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			40.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			17.5	mA
		Total of all pins (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			80.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			25.0	mA
	I_{OL2}	Per pin for P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V			0.4[Note 2]	mA
		Total of all pins (When duty ≤ 70%[Note 3])	2.7 V ≤ V_{DD} ≤ 5.5 V			2.8	mA

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the V_{SS} pin.

2. However, do not exceed the total current value.

3. Specification under conditions where the duty factor ≤ 70%.
The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (I_{OL} × 0.7)/(n × 0.01)

<Example> Where n = 80% and I_{OL} = –10.0 mA

Total output current of pins = (–10.0 × 0.7)/(80 × 0.01) ≅ – 8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V_{IH1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120 to P124, P137, P147, P200 to P206, EXCLK, EXCLKS, $\overline{\text{RESET}}$	Normal input buffer	0.8V_{DD}		V_{DD}	V
	V_{IH2}	P03, P10, P11	TTL input buffer 4.0 V ≤ V_{DD} ≤ 5.5 V	2.1		V_{DD}	V
			TTL input buffer 3.3 V ≤ V_{DD} < 4.0 V	2.0		V_{DD}	V
			TTL input buffer 2.7 V ≤ V_{DD} < 3.3 V	1.5		V_{DD}	V
Input voltage, low	V_{IL1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120 to P124, P137, P147, P200 to P206, EXCLK, EXCLKS, $\overline{\text{RESET}}$	Normal input buffer	0		0.2V_{DD}	V
	V_{IL2}	P03, P10, P11	TTL input buffer 4.0 V ≤ V_{DD} ≤ 5.5 V	0		0.8	V
			TTL input buffer 3.3 V ≤ V_{DD} < 4.0 V	0		0.5	V
			TTL input buffer 2.7 V ≤ V_{DD} < 3.3 V	0		0.32	V

Caution The maximum value of V_{IH} of pins P02, P10 to P12 is V_{DD}, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	V_{OH1}	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V, I_{OH1} = –3.0 mA	V_{DD} – 0.7			V
			2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OH1} = –1.0 mA	V_{DD} – 0.5			V
	V_{OH2}	P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OH2} = –100 μA	V_{DD} – 0.5			V
Output voltage, low	V_{OL1}	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V, I_{OL1} = 8.5 mA			0.7	V
			4.0 V ≤ V_{DD} ≤ 5.5 V, I_{OL1} = 4.0 mA			0.4	V
			2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OL1} = 1.5 mA			0.4	V
	V_{OL2}	P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OL2} = 400 μA			0.4	V

Caution P02, P10 to P12 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = −40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Input leakage current, high	I_{LIH1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120, P137, P147, P200 to P206, $\overline{\text{RESET}}$	$V_I = V_{DD}$				1	μA
	I_{LIH2}	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	$V_I = V_{DD}$	In input port or external clock input			1	μA
				In resonator connection			10	μA
Input leakage current, low	I_{LIL1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120, P137, P147, P200 to P206, $\overline{\text{RESET}}$	$V_I = V_{SS}$				−1	μA
	I_{LIL2}	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	$V_I = V_{SS}$	In input port or external clock input			−1	μA
				In resonator connection			−10	μA
On-chip pull-up resistance	R_U	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	$V_I = V_{SS}$, In input port		10	20	100	kΩ

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

2.3.2 Supply current characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V) (1/2)

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Supply current Note 1	I_{DD1}	Operating mode	HS (high-speed main) mode Note 5	f_{IH} = 32 MHz Note 3	V_{DD} = 5.0 V		5.0	7.5	mA
					V_{DD} = 3.0 V		5.0	7.5	mA
				f_{IH} = 24 MHz Note 3	V_{DD} = 5.0 V		3.9	5.8	mA
					V_{DD} = 3.0 V		3.9	5.8	mA
				f_{IH} = 16 MHz Note 3	V_{DD} = 5.0 V		2.9	4.2	mA
					V_{DD} = 3.0 V		2.9	4.2	mA
			LS (low-speed main) mode Note 5	f_{IH} = 8 MHz Note 3, T_A = –40 to + 85°C	V_{DD} = 3.0 V		1.3	2.0	mA
			HS (high-speed main) mode Note 5	f_{MX} = 20 MHz Note 2, V_{DD} = 5.0 V	Square wave input		3.2	4.9	mA
					Resonator connection		3.3	5.0	mA
				f_{MX} = 20 MHz Note 2, V_{DD} = 3.0 V	Square wave input		3.2	4.9	mA
					Resonator connection		3.3	5.0	mA
				f_{MX} = 10 MHz Note 2, V_{DD} = 5.0 V	Square wave input		2.0	2.9	mA
					Resonator connection		2.0	2.9	mA
				f_{MX} = 10 MHz Note 2, V_{DD} = 3.0 V	Square wave input		2.0	2.9	mA
					Resonator connection		2.0	2.9	mA
			LS (low-speed main) mode Note 5	f_{MX} = 8 MHz Note 2, V_{DD} = 3.0 V, T_A = –40 to + 85°C	Square wave input		1.2	1.8	mA
					Resonator connection		1.2	1.8	mA
			HS (high-speed main) mode Note 5	f_{IH} = 4 MHz Note 3 f_{PLL} = 64 MHz, f_{CLK} = 32 MHz	V_{DD} = 5.0 V		5.4	8.5	mA
					V_{DD} = 3.0 V		5.4	8.5	mA
				f_{IH} = 4 MHz Note 3 f_{PLL} = 64 MHz, f_{CLK} = 16 MHz	V_{DD} = 5.0 V		3.3	5.7	mA
					V_{DD} = 3.0 V		3.3	5.7	mA
			Subsystem clock operation	f_{SUB} = 32.768 kHz Note 4 T_A = –40°C	Square wave input		4.2	6.0	μA
					Resonator connection		4.4	6.2	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +25°C	Square wave input		4.2	6.0	μA
					Resonator connection		4.4	6.2	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +50°C	Square wave input		4.3	7.2	μA
					Resonator connection		4.5	7.4	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +70°C	Square wave input		4.4	8.1	μA
					Resonator connection		4.6	8.3	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +85°C	Square wave input		5.2	11.4	μA
					Resonator connection		5.4	11.6	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +105°C	Square wave input		6.9	20.8	μA
					Resonator connection		7.1	21.0	μA

(**Notes** and **Remarks** are listed on the next page.)

Notes 1. Total current flowing into V_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD} or V_{SS}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, comparator, programmable gain amplifier, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

2. When high-speed on-chip oscillator and subsystem clock are stopped.

3. When high-speed system clock and subsystem clock are stopped.

4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.

5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 32 MHz

LS (low-speed main) mode: 2.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 8 MHz

Remarks 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

2. f_{IH}: High-speed on-chip oscillator clock frequency

3. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

4. Except subsystem clock operation, temperature condition of the TYP. value is T_A = 25°C

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V) (2/2)

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Supply current Note 1	I_{DD2} Note 2	HALT mode	HS (high-speed main) mode Note 7	f_{IH} = 32 MHz Note 4	V_{DD} = 5.0 V		0.72	2.9	mA
					V_{DD} = 3.0 V		0.72	2.9	mA
				f_{IH} = 24 MHz Note 4	V_{DD} = 5.0 V		0.57	2.3	mA
					V_{DD} = 3.0 V		0.57	2.3	mA
				f_{IH} = 16 MHz Note 4	V_{DD} = 5.0 V		0.50	1.7	mA
					V_{DD} = 3.0 V		0.50	1.7	mA
			LS (low-speed main) mode Note 7	f_{IH} = 8 MHz Note 4, T_A = –40 to +85°C	V_{DD} = 3.0 V		320	910	μA
			HS (high-speed main) mode Note 7	f_{MX} = 20 MHz Note 3, V_{DD} = 5.0 V	Square wave input		0.40	1.9	mA
					Resonator connection		0.50	2.0	mA
				f_{MX} = 20 MHz Note 3, V_{DD} = 3.0 V	Square wave input		0.40	1.9	mA
					Resonator connection		0.50	2.0	mA
				f_{MX} = 10 MHz Note 3, V_{DD} = 5.0 V	Square wave input		0.24	1.02	mA
					Resonator connection		0.30	1.08	mA
				f_{MX} = 10 MHz Note 3, V_{DD} = 3.0 V	Square wave input		0.24	1.02	mA
					Resonator connection		0.30	1.08	mA
			LS (low-speed main) mode Note 7	f_{MX} = 8 MHz Note 3, V_{DD} = 3.0 V, T_A = –40 to +85°C	Square wave input		130	720	μA
					Resonator connection		170	760	μA
			HS (high-speed main) mode Note 7	f_{IH} = 4 MHz Note 4 f_{PLL} = 64 MHz, f_{CLK} = 32 MHz	V_{DD} = 5.0 V		1.15	4.0	mA
					V_{DD} = 3.0 V		1.15	4.0	mA
				f_{IH} = 4 MHz Note 4 f_{PLL} = 64 MHz, f_{CLK} = 16 MHz	V_{DD} = 5.0 V		0.95	3.2	mA
					V_{DD} = 3.0 V		0.95	3.2	mA
			Subsystem clock operation	f_{SUB} = 32.768 kHz Note 5 T_A = –40°C	Square wave input		0.28	0.70	μA
					Resonator connection		0.47	0.89	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +25°C	Square wave input		0.33	0.70	μA
					Resonator connection		0.52	0.89	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +50°C	Square wave input		0.41	1.90	μA
					Resonator connection		0.60	2.09	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +70°C	Square wave input		0.54	2.80	μA
					Resonator connection		0.73	2.99	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +85°C	Square wave input		1.27	6.10	μA
					Resonator connection		1.46	6.29	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +105°C	Square wave input		3.04	15.5	μA
					Resonator connection		3.23	15.7	μA
	I_{DD3} Note 6	STOP mode Note 8	T_A = –40°C				0.18	0.50	μA
			T_A = +25°C				0.23	0.50	μA
			T_A = +50°C				0.27	1.70	μA
			T_A = +70°C				0.44	2.60	μA
			T_A = +85°C				1.17	5.90	μA
			T_A = +105°C				2.94	15.3	μA

(**Notes** and **Remarks** are listed on the next page.)

Notes 1. Total current flowing into V_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD} or V_{SS}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, comparator, programmable gain amplifier, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

2. During HALT instruction execution by flash memory.

3. When high-speed on-chip oscillator and subsystem clock are stopped.

4. When high-speed system clock and subsystem clock are stopped.

5. When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.

6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.

7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 32 MHz

LS (low-speed main) mode: 2.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 8 MHz

8. Regarding the value for current operate the subsystem clock in STOP mode, refer to that in HALT mode.

Remarks 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

2. f_{IH}: High-speed on-chip oscillator clock frequency

3. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is T_A = 25°C

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	I_{FIL} Note 1				0.20		μA
RTC operating current	I_{RTC} Notes 1, 2, 3				0.02		μA
12-bit interval timer operating current	I_{IT} Notes 1, 2, 4				0.02		μA
Watchdog timer operating current	I_{WDT} Notes 1, 2, 5	f_{IL} = 15 kHz			0.22		μA
A/D converter operating current	I_{ADC} Notes 1, 6	When conversion at maximum speed	Normal mode, AV_{REFP} = V_{DD} = 5.0 V		1.3	1.7	mA
			Low voltage mode, AV_{REFP} = V_{DD} = 3.0 V		0.5	0.7	mA
A/D converter reference voltage current	I_{ADREF} Note 1				75.0		μA
Temperature sensor operating current	I_{TMPS} Note 1				75.0		μA
LVD operating current	I_{LVD} Notes 1, 7				0.08		μA
Self-programming operating current	I_{FSP} Notes 1, 8				2.50	12.2	mA
Programmable gain amplifier operating current	I_{PGA} Note 9		AV_{REFP} = V_{DD} = 5.0 V		0.21	0.31	mA
			AV_{REFP} = V_{DD} = 3.0 V		0.18	0.29	mA
Comparator operating current	I_{CMP} Note 10	When one comparator channel is operating	AV_{REFP} = V_{DD} = 5.0 V		41.4	62	μA
			AV_{REFP} = V_{DD} = 3.0 V		37.2	59	μA
	I_{VREF}	When one internal reference voltage circuit is operating	AV_{REFP} = V_{DD} = 5.0 V		14.8	26	μA
			AV_{REFP} = V_{DD} = 3.0 V		8.9	20	μA
Programmable gain amplifier/ comparator reference current source	I_{IREF} Note 11		AV_{REFP} = V_{DD} = 5.0 V		3.2	5.1	μA
			AV_{REFP} = V_{DD} = 3.0 V		2.9	4.9	μA
BGO operating current	I_{BGO} Note 12				2.50	12.2	mA
SNOOZE operating current	I_{SNOZ} Note 1	ADC operation	The mode is performed Note 13		0.50	1.1	mA
			The A/D conversion operations are performed, Standard mode, AV_{REFP} = V_{DD} = 5.0 V		2.0	3.04	mA
		CSI/UART operation			0.70	1.54	mA

(**Notes** and **Remarks** are listed on the next page.)

Notes 1. Current flowing to the V_{DD}.

2. When the high-speed on-chip oscillator and high-speed system clock are stopped.

3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either I_{DD1} or I_{DD2}, and I_{RTC}, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, I_{FIL} should be added. I_{DD2} subsystem clock operation includes the operational current of the real-time clock.

4. Current flowing only to the 12-bit interval timer (excluding the operating current of the XT1 oscillator and f_{IL} operating current). The current of the RL78 microcontrollers is the sum of the values of either I_{DD1} or I_{DD2}, and I_{IT}, when the 12-bit interval timer operates in operation mode or HALT mode.

5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3} and I_{WDT} when the watchdog timer is in operation.

6. Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of I_{DD1} or I_{DD2} and I_{ADC} when the A/D converter operates in an operation mode or the HALT mode.

7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3} and I_{LVD} when the LVD circuit is in operation.

8. Current flowing during self-programming operation.

9. Current flowing only to the programmable gain amplifier. The supply current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3}, and I_{PGA}, when the programmable gain amplifier is operating in operating mode or in HALT mode.

10. Current flowing only to the comparator. The supply current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3}, and I_{CMP}, when the comparator is operating.

11. This is the current required to flow to V_{DD} pin of the current circuit that is used as the programmable gain amplifier and the comparator.

12. Current flowing only during data flash rewrite.

13. See **21.3.3 SNOOZE mode in the RL78/I1A User's Manual** for shift time to the SNOOZE mode .

Remarks 1. f_{IL}: Low-speed on-chip oscillator clock frequency

2. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

3. f_{CLK}: CPU/peripheral hardware clock frequency

4. Temperature condition of the TYP. value is T_A = 25°C

5. Example of calculating current value when using programmable gain amplifier and comparator.

Examples 1) TYP. operating current value when three comparator channels, one internal reference voltage generator, and PGA are operating (when AV_{REFP} = V_{DD} = 5.0 V)

$I_{CMP} \times 3 + I_{VREF} + I_{PGA} + I_{IREF}$

= 41.4 [μA] × 3 + 14.8 [μA] × 1 + 210 [μA] + 3.2 [μA]

= 352.2 [μA]

Examples 2) TYP. operating current value when using two comparator channels, without using internal reference voltage generator (when AV_{REFP} = V_{DD} = 5.0 V)

$I_{CMP} \times 2 + I_{IREF}$

= 41.4 [μA] × 2 + 3.2 [μA]

= 86.0 [μA]

2.4 AC Characteristics

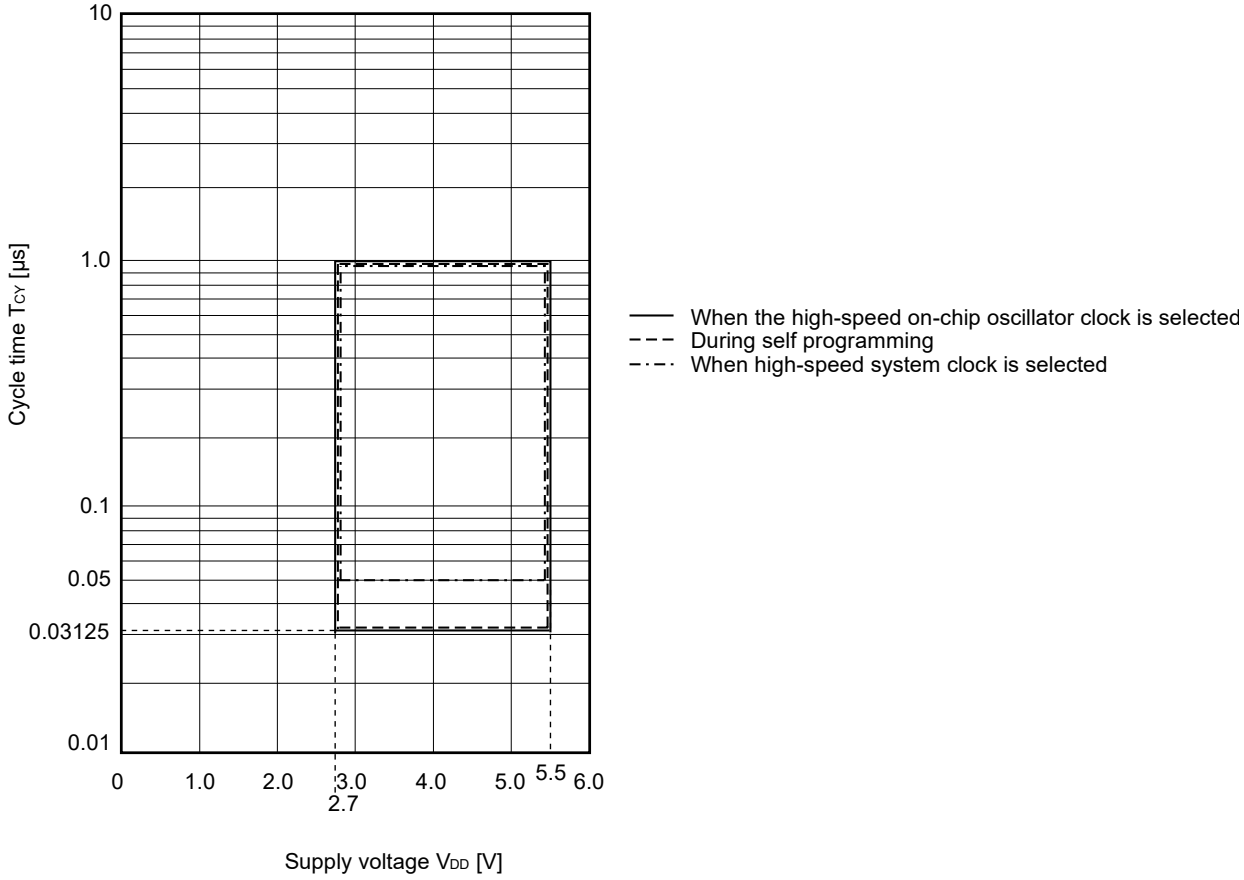
(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum instruction execution time)	T_{CY}	Main system clock (f_{MAIN}) operation	HS (high-speed main) mode		0.03125		1	μs
			LS (low-speed main) mode	T_A = –40 to +85°C	0.125		1	μs
		Subsystem clock (f_{SUB}) operation			28.5	30.5	31.3	μs
		In the self programming mode	HS (high-speed main) mode		0.03125		1	μs
			LS (low-speed main) mode	T_A = –40 to +85°C	0.125		1	μs
External system clock frequency	f_{EX}				1.0		20.0	MHz
	f_{EXS}				32		35	kHz
External system clock input high-level width, low-level width	t_{EXH}, t_{EXL}				24			ns
	t_{EXHS}, t_{EXLS}				13.7			μs
TI03, TI05, TI06, TI07 input high-level width, low-level width	t_{TIH}, t_{TIL}				2/f_{MCK}+10			ns
TO03, TO05, TO06, TKBO00, TKBO01, TKBO10, TKBO11, TKBO20, TKBO21, TKCO00 to TKCO05 output frequency (When duty = 50%)	f_{TO}	HS (high-speed main) mode		4.0 V ≤ V_{DD} ≤ 5.5 V			8	MHz
				2.7 V ≤ V_{DD} < 4.0 V			4	MHz
		LS (low-speed main) mode, T_A = –40 to +85°C		4.0 V ≤ V_{DD} ≤ 5.5 V			4	MHz
				2.7 V ≤ V_{DD} < 4.0 V			2	MHz
Interrupt input high-level width, low-level width	t_{INTH}, t_{INTL}	INTP0, INTP3, INTP4, INTP9 to INTP11, INTP20 to INTP23			1			μs
$\overline{RESET}$ low-level width	t_{RSL}				10			μs

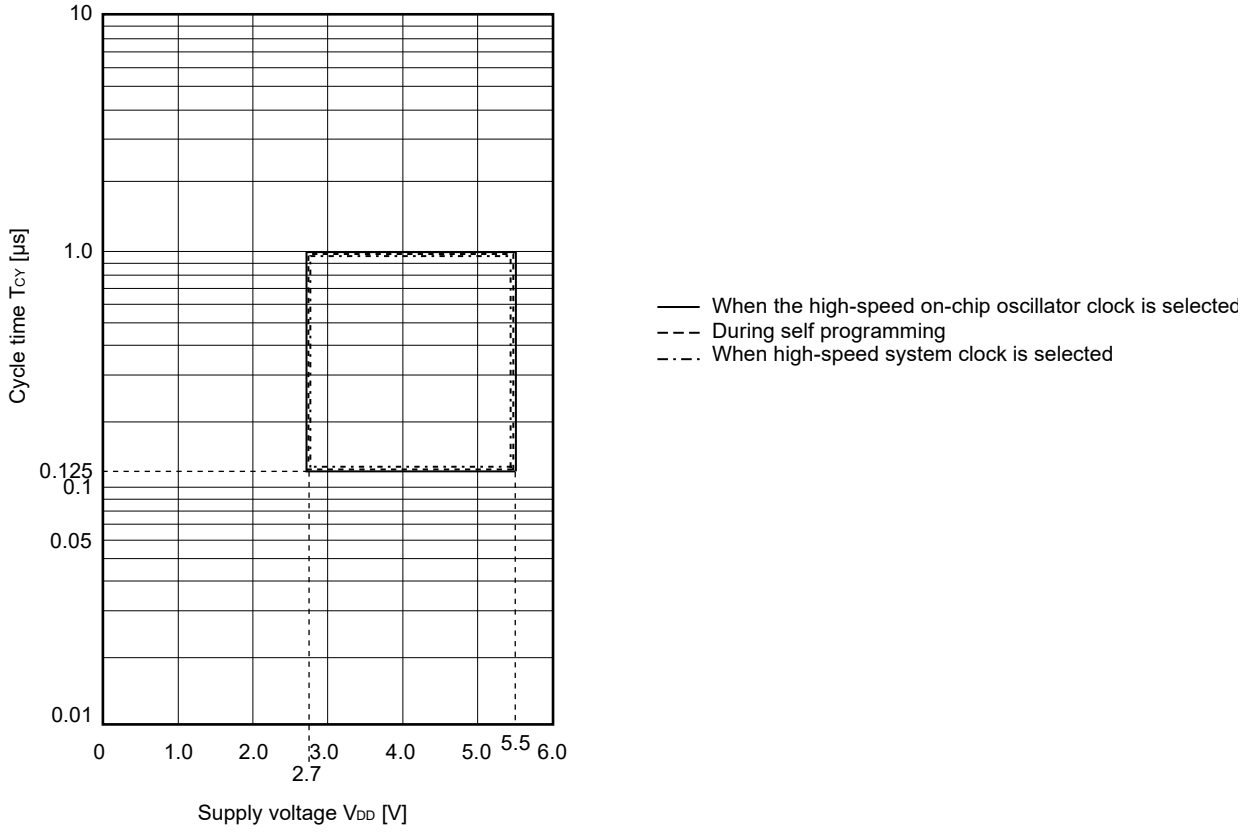
Remark f_{MCK}: Timer array unit operation clock frequency
(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

Minimum Instruction Execution Time during Main System Clock Operation

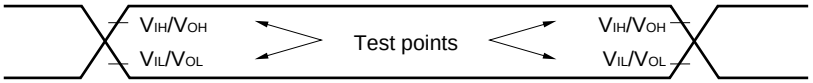
T_{CY} vs V_{DD} (HS (high-speed main) mode)



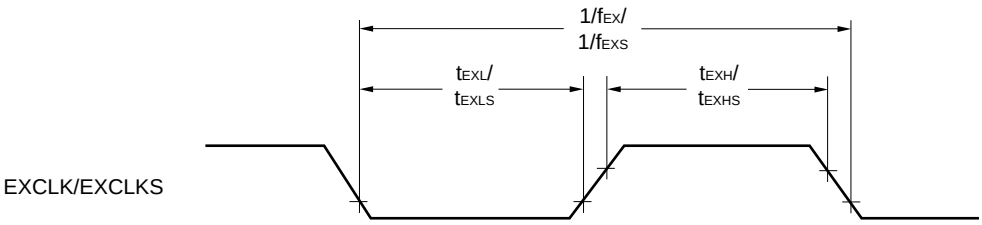
T_{CY} vs V_{DD} (LS (low-speed main) mode)



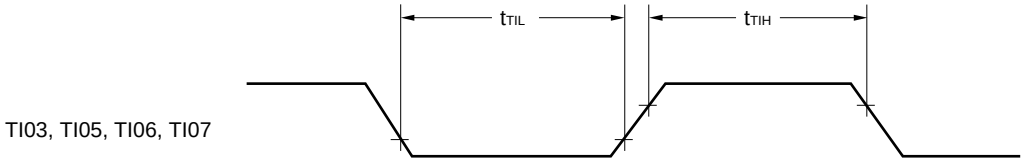
AC Timing Test Points

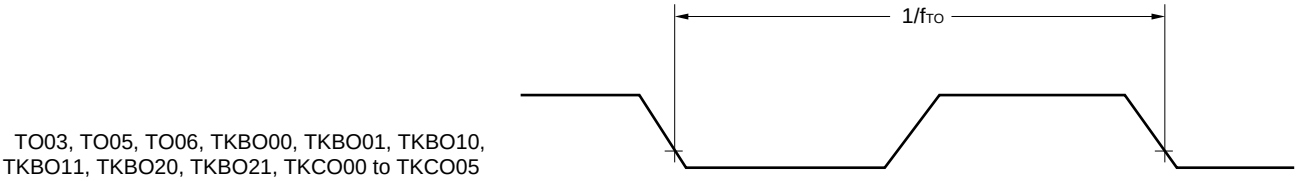


External System Clock Timing

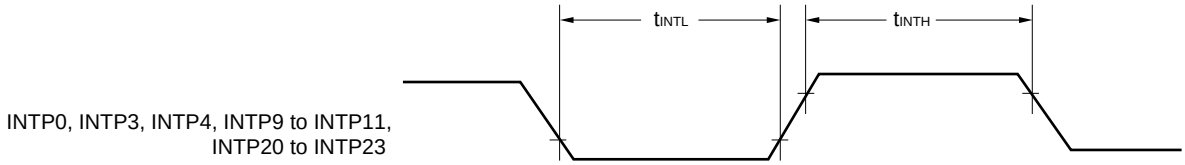


TI/TO Timing

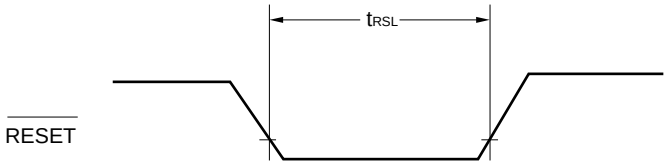




Interrupt Request Input Timing

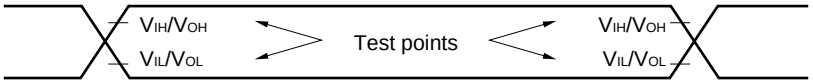


$\overline{\text{RESET}}$ Input Timing



2.5 Peripheral Functions Characteristics

AC Timing Test Points



2.5.1 Serial array unit 0, 4 (UART0, UART1, CSI00, DALI/UART4)

(1) During communication at same potential (UART mode)

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

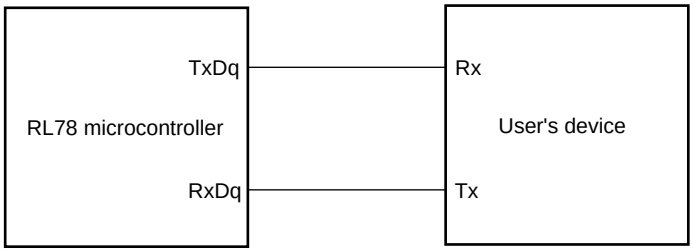
Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
Transfer rate[Note 1]		2.7 V≤ V_{DD} ≤ 5.5 V		f_{MCK}/6		f_{MCK}/6	bps
		Theoretical value of the maximum transfer rate f_{MCK} = f_{CLK}[Note 2]		5.3		1.3	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

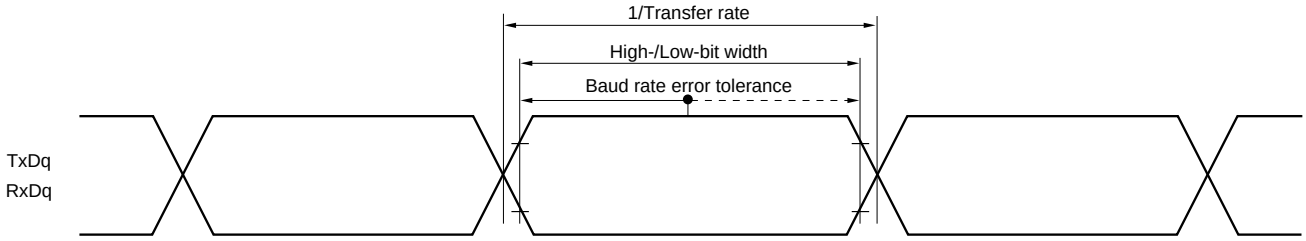
2. The maximum operating frequencies of the CPU/peripheral hardware clock (f_{CLK}) are:
HS (high-speed main) mode: 32 MHz (2.7 V ≤ V_{DD} ≤ 5.5 V)
LS (low-speed main) mode: 8 MHz (2.7 V ≤ V_{DD} ≤ 5.5 V), T_A = –40 to +85°C

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

2. f_{MCK}: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03))

(2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output)

(T_A = –40 to +105°C[Note 5], 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t_{KCY1}	$t_{KCY1} \geq 4/f_{CLK}$	125		500		ns
SCKp high-/low-level width	t_{KH1}, t_{KL1}	4.0 V ≤ V_{DD} ≤ 5.5 V	$t_{KCY1}/2 - 12$		$t_{KCY1}/2 - 50$		ns
		2.7 V ≤ V_{DD} ≤ 5.5 V	$t_{KCY1}/2 - 18$		$t_{KCY1}/2 - 50$		ns
SIp setup time (to SCKp↑) Note 1	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V	44		110		ns
		2.7 V ≤ V_{DD} ≤ 5.5 V	44		110		ns
SIp hold time (from SCKp↑) Note 2	t_{KSI1}		19		19		ns
Delay time from SCKp↓ to SOp output Note 3	t_{KSO1}	C = 30 pF Note 4		25		25	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

4. C is the load capacitance of the SCKp and SOp output lines.

5. Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

2. f_{MCK}: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))

(3) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input)

(T_A = –40 to +105°C[Note 6], 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time [Note 5]	t_{KCY2}	4.0 V ≤ V_{DD} ≤ 5.5 V	20 MHz < f_{MCK}	8/f_{MCK}		–		ns
			f_{MCK} ≤ 20 MHz	6/f_{MCK}		6/f_{MCK}		ns
		2.7 V ≤ V_{DD} ≤ 5.5 V	16 MHz < f_{MCK}	8/f_{MCK}		–		ns
			f_{MCK} ≤ 16 MHz	6/f_{MCK}		6/f_{MCK}		ns
SCKp high-/low-level width	t_{KH2}, t_{KL2}			t_{KCY2}/2		t_{KCY2}/2		ns
SIp setup time (to SCKp↑)[Note 1]	t_{SIK2}			1/f_{MCK}+20		1/f_{MCK}+30		ns
SIp hold time (from SCKp↑)[Note 2]	t_{KSI2}			1/f_{MCK}+31		1/f_{MCK}+31		ns
Delay time from SCKp↓ to SOp output[Note 3]	t_{KSO2}	C = 30 pF[Note 4]			2/f_{MCK}+ 44		2/f_{MCK}+ 110	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

4. C is the load capacitance of the SOp output lines.

5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

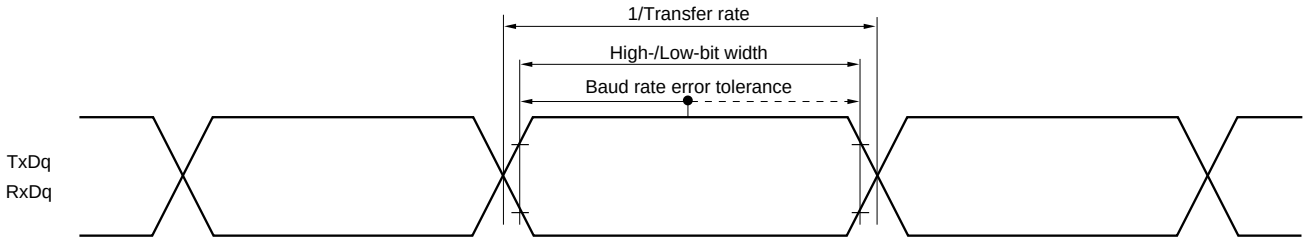
6. Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

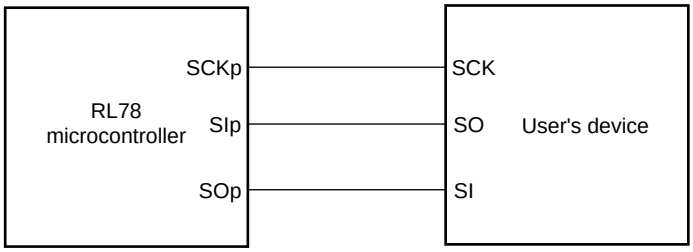
Remarks 1. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

2. f_{MCK}: Serial array unit operation clock frequency

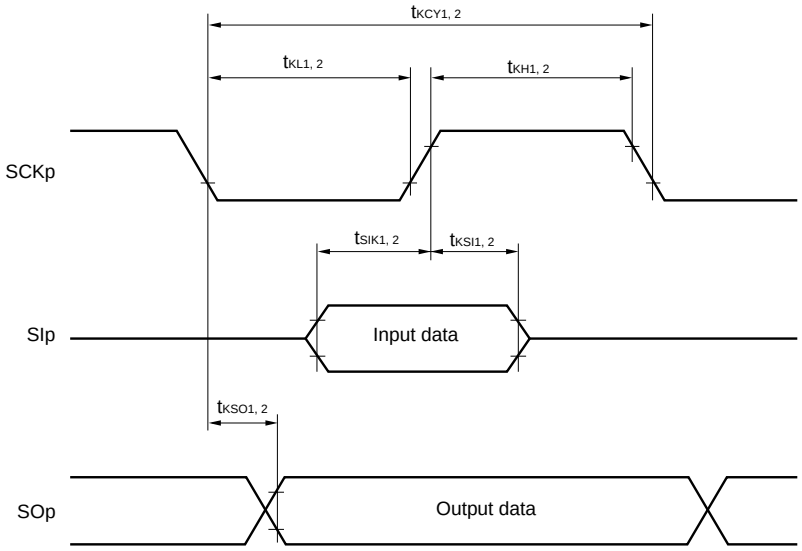
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))



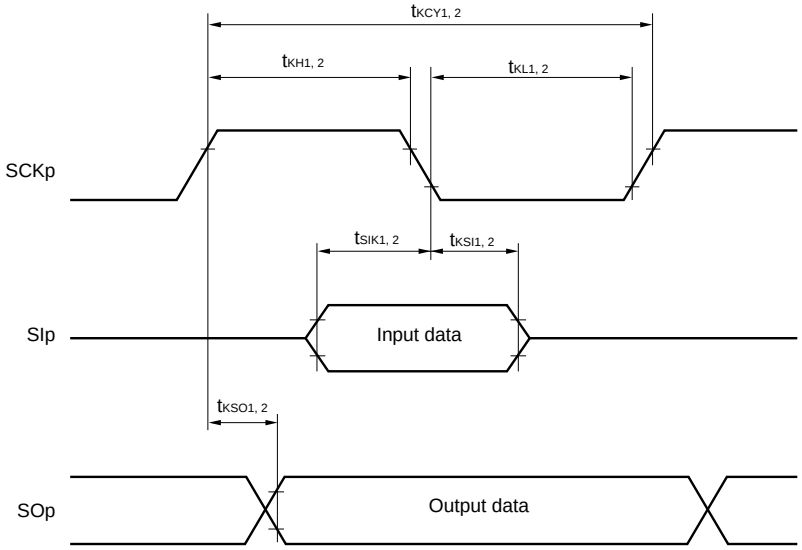
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00)

2. m: Unit number, n: Channel number (mn = 00)

(4) Communication at different potential (2.5 V, 3 V) (UART mode) (1/2)

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
Transfer rate		Reception	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V		$f_{MCK}/6$ Note 1		$f_{MCK}/6$ Note 1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		5.3		1.3	Mbps
			2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V		$f_{MCK}/6$ Note 1		$f_{MCK}/6$ Note 1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		5.3		1.3	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (f_{CLK}) are:

HS (high-speed main) mode: 32 MHz (2.7 V ≤ V_{DD} ≤ 5.5 V)

LS (low-speed main) mode: 8 MHz (2.7 V ≤ V_{DD} ≤ 5.5 V), T_A = –40 to +85°C.

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Remarks 1. V_b[V]: Communication line voltage

2. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

3. f_{MCK}: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03)

(4) Communication at different potential (2.5 V, 3 V) (UART mode) (2/2)

(T_A = –40 to +105°C Note 5, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
Transfer rate		Transmission	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V		**Note 1**		**Note 1**	bps
			Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 1.4 kΩ, V_b = 2.7 V		2.8 Note 2		2.8 Note 2	Mbps
			2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V		**Note 3**		**Note 3**	bps
			Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 2.7 kΩ, V_b = 2.3 V		1.2 Note 4		1.2 Note 4	Mbps

Notes 1. The smaller maximum transfer rate derived by using f_{MCK}/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V ≤ V_{DD} ≤ 5.5 V and 2.7 V ≤ V_b ≤ 4.0 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \text{ [\%]}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

2. This value as an example is calculated when the conditions described in the “Conditions” column are met. See **Note 1** above to calculate the maximum transfer rate under conditions of the customer.

3. The smaller maximum transfer rate derived by using f_{MCK}/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V ≤ V_{DD} < 4.0 V and 2.3 V ≤ V_b ≤ 2.7 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \text{ [\%]}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

4. This value as an example is calculated when the conditions described in the “Conditions” column are met. See **Note 3** above to calculate the maximum transfer rate under conditions of the customer.

5. Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Remarks 1. R_b[Ω]: Communication line (TxDq) pull-up resistance,
C_b[F]: Communication line (TxDq) load capacitance, V_b[V]: Communication line voltage

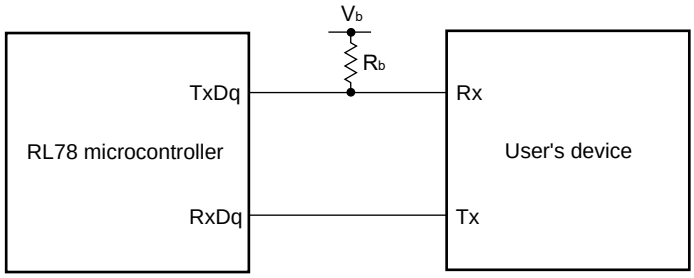
2. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

3. f_{MCK}: Serial array unit operation clock frequency

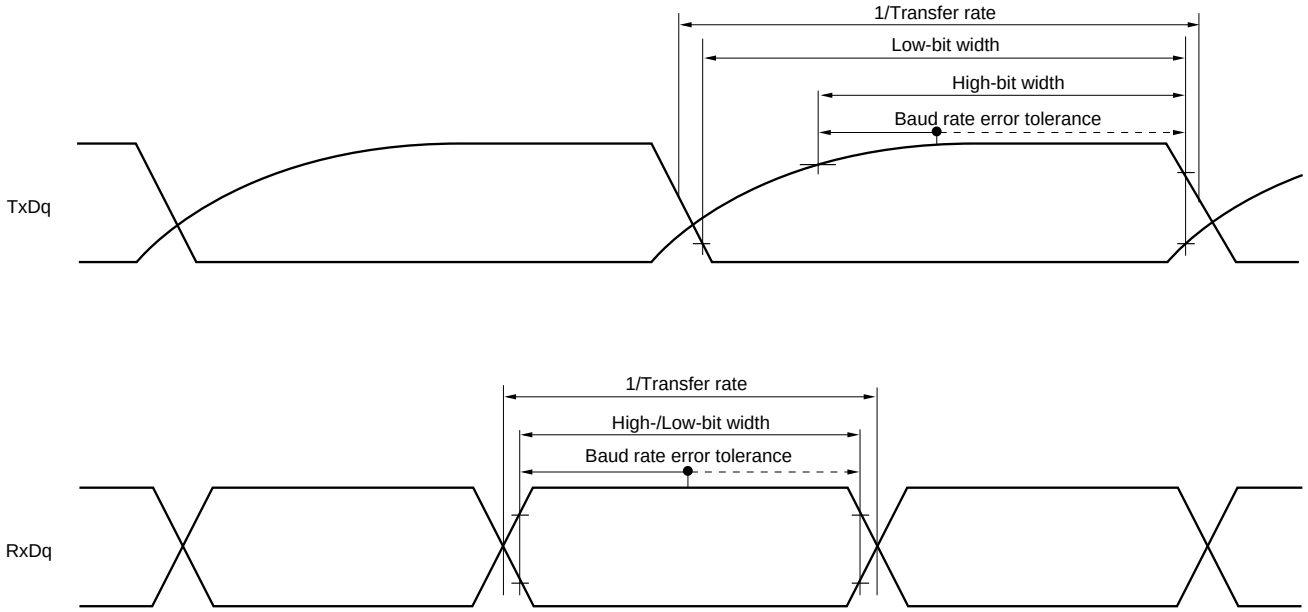
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03))

UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)



Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. R_b[Ω]: Communication line (TxDq) pull-up resistance, V_b[V]: Communication line voltage

2. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

(5) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)

(T_A = –40 to +105°C Note 3, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t_{KCY1}	$t_{KCY1} \geq 2/f_{CLK}$	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ	200		1150		ns
			2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ	300		1150		ns
SCKp high-level width	t_{KH1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		t_{KCY1}/2 – 50		t_{KCY1}/2 – 75		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		t_{KCY1}/2 – 120		t_{KCY1}/2 – 170		ns
SCKp low-level width	t_{KL1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		t_{KCY1}/2 – 7		t_{KCY1}/2 – 50		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		t_{KCY1}/2 – 10		t_{KCY1}/2 – 50		ns
SIp setup time (to SCKp↑) Note 1	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		81		479		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		177		479		ns
SIp hold time (from SCKp↑) Note 1	t_{KSI1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		10		19		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		10		19		ns
Delay time from SCKp↓ to SOp output Note 1	t_{KSO1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ			60		100	ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ			130		195	ns
SIp setup time (to SCKp↓) Note 2	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		44		110		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		44		110		ns
SIp hold time (from SCKp↓) Note 2	t_{KSI1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		10		19		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		10		19		ns
Delay time from SCKp↑ to SOp output Note 2	t_{KSO1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ			10		25	ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ			10		25	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Remarks 1. R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage

2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

(6) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)

(T_A = –40 to +105°C Note 3, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

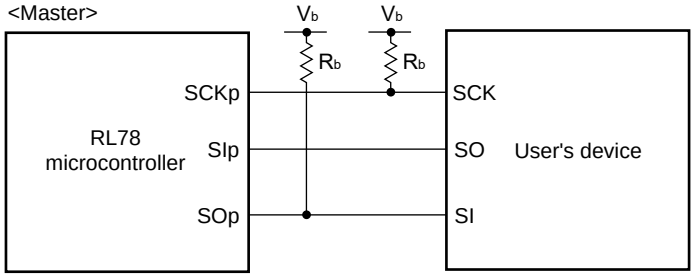
Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t_{KCY1}	$t_{KCY1} \geq 4/f_{CLK}$	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ	300		1150		ns
			2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ	500		1150		ns
SCKp high-level width	t_{KH1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		t_{KCY1}/2 – 75		t_{KCY1}/2 – 75		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		t_{KCY1}/2 – 170		t_{KCY1}/2 – 170		ns
SCKp low-level width	t_{KL1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		t_{KCY1}/2 – 12		t_{KCY1}/2 – 50		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		t_{KCY1}/2 – 18		t_{KCY1}/2 – 50		ns
SIp setup time (to SCKp↑) Note 1	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		81		479		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		177		479		ns
SIp hold time (from SCKp↑) Note 1	t_{KSI1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		19		19		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		19		19		ns
Delay time from SCKp↓ to SOp output Note 1	t_{KSO1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ			100		100	ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ			195		195	ns
SIp setup time (to SCKp↓) Note 2	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		44		110		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		44		110		ns
SIp hold time (from SCKp↓) Note 2	t_{KSI1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, Cb = 30 pF, Rb = 1.4 kΩ		19		19		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, Cb = 30 pF, Rb = 2.7 kΩ		19		19		ns
Delay time from SCKp↑ to SOp output Note 2	t_{KSO1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, Cb = 30 pF, Rb = 1.4 kΩ			25		25	ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, Cb = 30 pF, Rb = 2.7 kΩ			25		25	ns

Notes
1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
3. Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

(**Caution** and **Remarks** are listed on the next page.)

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

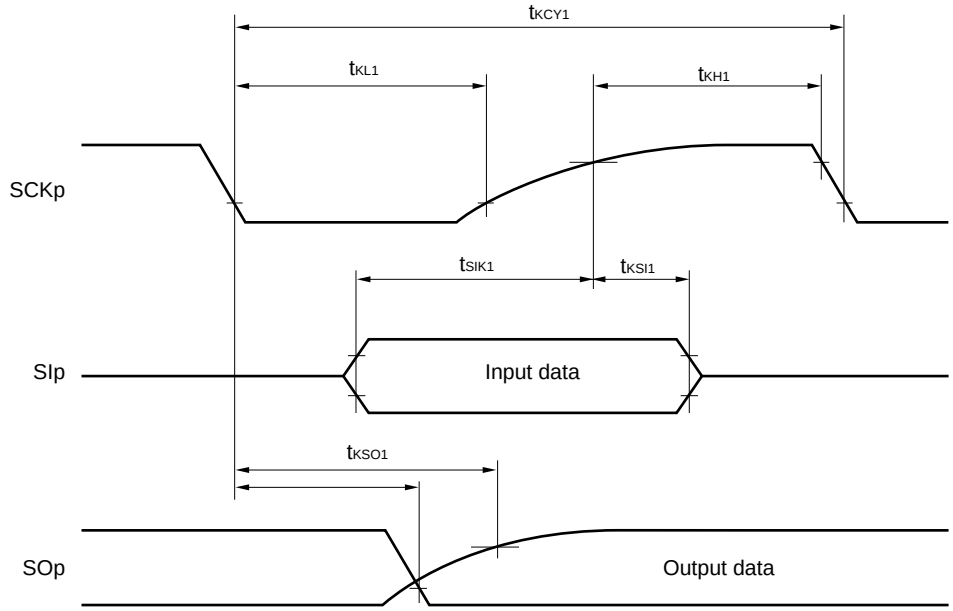
CSI mode connection diagram (during communication at different potential)



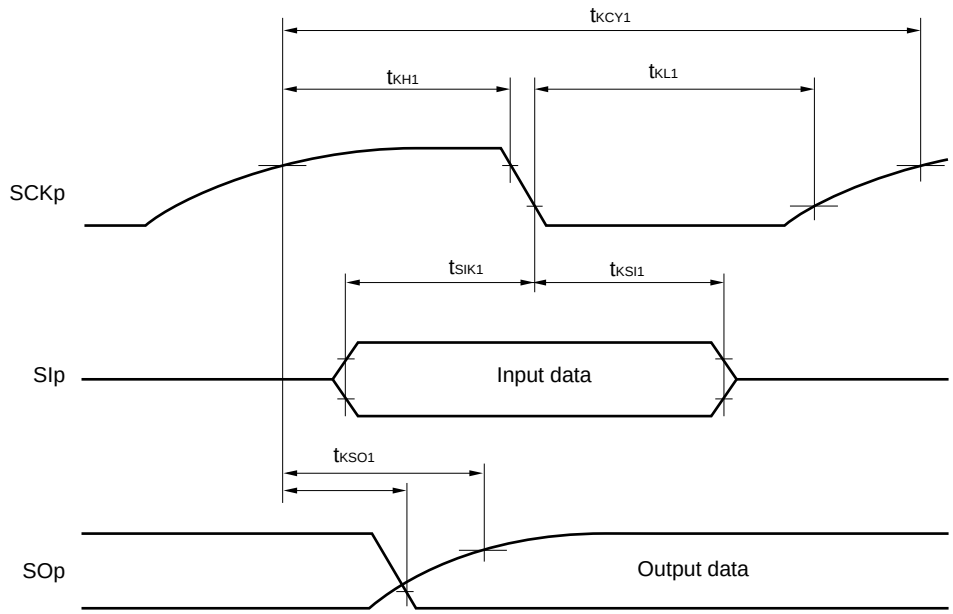
Remarks 1. R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage

2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

CSI mode serial transfer timing (master mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (master mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

(7) DALI/UART4 mode

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
Transfer rate					f_{MCK}/12		f_{MCK}/12	bps
			Maximum transfer rate theoretical value HS: f_{CLK} = 32 MHz, f_{MCK} = f_{CLK} LS: f_{CLK} = 8 MHz, f_{MCK} = f_{CLK}		2.6		0.6	Mbps

Remark f_{MCK}: Operation clock frequency of DALI/UART.
(Operation clock to be set by the serial clock select register mn (SPS4).)

Caution Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

2.5.2 Serial interface IICA

(1) I^2C standard mode

(T_A = –40 to +105°C [Note 3], 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	f_{SCL}	Standard mode: f_{CLK} ≥ 1 MHz	0	100	0	100	kHz
Setup time of restart condition	$t_{SU:STA}$		4.7		4.7		μs
Hold time[Note 1]	$t_{HD:STA}$		4.0		4.0		μs
Hold time when SCLA0 = “L”	t_{LOW}		4.7		4.7		μs
Hold time when SCLA0 = “H”	t_{HIGH}		4.0		4.0		μs
Data setup time (reception)	$t_{SU:DAT}$		250		250		ns
Data hold time (transmission)[Note 2]	$t_{HD:DAT}$		0	3.45	0	3.45	μs
Setup time of stop condition	$t_{SU:STO}$		4.0		4.0		μs
Bus-free time	t_{BUF}		4.7		4.7		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of $t_{HD:DAT}$ is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

3. Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

Remark The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: C_b = 400 pF, R_b = 2.7 kΩ

(2) I^2C fast mode

(T_A = –40 to +105°C Note 3, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	f_{SCL}	fast mode: f_{CLK} ≥ 3.5 MHz	0	400	0	400	kHz
Setup time of restart condition	$t_{SU:STA}$		0.6		0.6		μs
Hold time Note 1	$t_{HD:STA}$		0.6		0.6		μs
Hold time when SCLA0 = “L”	t_{LOW}		1.3		1.3		μs
Hold time when SCLA0 = “H”	t_{HIGH}		0.6		0.6		μs
Data setup time (reception)	$t_{SU:DAT}$		100		100		ns
Data hold time (transmission) Note 2	$t_{HD:DAT}$		0	0.9	0	0.9	μs
Setup time of stop condition	$t_{SU:STO}$		0.6		0.6		μs
Bus-free time	t_{BUF}		1.3		1.3		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

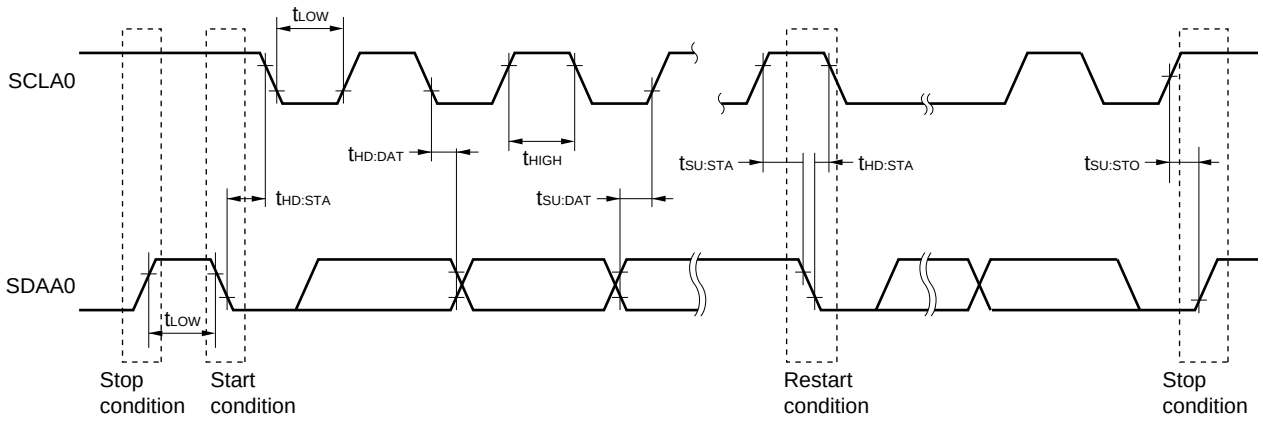
2. The maximum value (MAX.) of $t_{HD:DAT}$ is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

3. Operating conditions of LS (low-speed main) mode is T_A = –40 to +85°C.

Remark The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode: C_b = 320 pF, R_b = 1.1 kΩ

IICA serial transfer timing



2.6 Analog Characteristics

2.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel	Reference Voltage		
	Reference voltage (+) = AV_{REFP} Reference voltage (–) = AV_{REFM}	Reference voltage (+) = V_{DD} Reference voltage (–) = V_{SS}	Reference voltage (+) = V_{BGR} Reference voltage (–) = AV_{REFM}
ANI0 to ANI2, ANI4 to ANI7	See **2.6.1 (1)**.	See **2.6.1 (3)**.	See **2.6.1 (4)**.
ANI16 to ANI19	See **2.6.1 (2)**.		
Internal reference voltage Temperature sensor output voltage	See **2.6.1 (1)**.		–

(1) When reference voltage (+)= AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target pin: ANI2, ANI4 to ANI7, internal reference voltage, and temperature sensor output voltage

(T_A = –40 to +105°C, 2.7 V ≤ AV_{REFP} ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = AV_{REFP}, Reference voltage (–) = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error[Note 1]	AINL	10-bit resolution AV_{REFP} = V_{DD}[Note 3]			1.2	±3.5	LSB
Conversion time	t_{CONV}	10-bit resolution Target pin: ANI2, ANI4 to ANI7	3.6 V ≤ V_{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.1875		39	μs
		10-bit resolution Target pin: Internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	3.6 V ≤ V_{DD} ≤ 5.5 V	2.375		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.5625		39	μs
Zero-scale error[Notes 1, 2]	E_{ZS}	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±0.25	%FSR
Full-scale error[Notes 1, 2]	E_{FS}	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±0.25	%FSR
Integral linearity error[Note 1]	ILE	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±2.5	LSB
Differential linearity error[Note 1]	DLE	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±1.5	LSB
Analog input voltage	V_{AIN}	ANI2, ANI4 to ANI7		0		AV_{REFP}	V
		Internal reference voltage (HS (high-speed main) mode)		V_{BGR}[Note 4]			V
		Temperature sensor output voltage (HS (high-speed main) mode)		V_{TMPS25}[Note 4]			V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. When AV_{REFP} < V_{DD}, the MAX. values are as follows.

Overall error: Add ±1.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AV_{REFP} = V_{DD}.

Integral linearity error/Differential linearity error: Add ±0.5 LSB to the MAX. value when AV_{REFP} = V_{DD}.

4. See **2.6.2 Temperature sensor/internal reference voltage characteristics**.

(2) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target pin: ANI16 to ANI19

(T_A = –40 to +105°C, 2.7 V ≤ AV_{REFP} ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = AV_{REFP}, Reference voltage (–) = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error[Note 1]	AINL	10-bit resolution AV_{REFP} = V_{DD}[Notes 3]			1.2	±5.0	LSB
Conversion time	t_{CONV}	10-bit resolution Target ANI pin : ANI16 to ANI19	3.6 V ≤ V_{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.1875		39	μs
Zero-scale error[Notes 1, 2]	E_{ZS}	10-bit resolution AV_{REFP} = V_{DD}[Notes 3]				±0.35	%FSR
Full-scale error[Notes 1, 2]	E_{FS}	10-bit resolution AV_{REFP} = V_{DD}[Notes 3]				±0.35	%FSR
Integral linearity error[Note 1]	ILE	10-bit resolution AV_{REFP} = V_{DD}[Notes 3]				±3.5	LSB
Differential linearity error[Note 1]	DLE	10-bit resolution AV_{REFP} = V_{DD}[Notes 3]				±2.0	LSB
Analog input voltage	V_{AIN}	ANI16 to ANI19		0		AV_{REFP} and V_{DD}	V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. When AV_{REFP} < V_{DD}, the MAX. values are as follows.

Overall error: Add ±1.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AV_{REFP} = V_{DD}.

Integral linearity error/Differential linearity error: Add ±0.5 LSB to the MAX. value when AV_{REFP} = V_{DD}.

(3) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (–) = V_{SS} (ADREFM = 0), target pin: ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19, internal reference voltage, and temperature sensor output voltage

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = V_{DD}, Reference voltage (–) = V_{SS})

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error[Note 1]	AINL	10-bit resolution			1.2	±7.0	LSB
Conversion time	t_{CONV}	10-bit resolution Target pin: ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19	3.6 V ≤ V_{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.1875		39	μs
Conversion time	t_{CONV}	10-bit resolution Target pin: Internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	3.6 V ≤ V_{DD} ≤ 5.5 V	2.375		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.5625		39	μs
Zero-scale error[Notes 1, 2]	E_{ZS}	10-bit resolution				±0.60	%FSR
Full-scale error[Notes 1, 2]	E_{FS}	10-bit resolution				±0.60	%FSR
Integral linearity error[Note 1]	ILE	10-bit resolution				±4.0	LSB
Differential linearity error[Note 1]	DLE	10-bit resolution				±2.0	LSB
Analog input voltage	V_{AIN}	ANI0 to ANI2, ANI4 to ANI7		0		V_{DD}	V
		ANI16 to ANI19		0		V_{DD}	V
		Internal reference voltage (HS (high-speed main) mode)		V_{BGR}[Note 3]			V
		Temperature sensor output voltage (HS (high-speed main) mode)		V_{TMPS25}[Note 3]			V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. See **2.6.2 Temperature sensor/internal reference voltage characteristics**.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target pin: ANI0, ANI2, ANI4 to ANI7, ANI16 to ANI19

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = V_{BGR}[Note 3], Reference voltage (–) = AV_{REFM} = 0 V[Note 4], HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	RES		8			bit
Conversion time	t_{CONV}	8-bit resolution	17		39	μs
Zero-scale error[Notes 1, 2]	E_{ZS}	8-bit resolution			±0.60	%FSR
Integral linearity error[Note 1]	ILE	8-bit resolution			±2.0	LSB
Differential linearity error[Note 1]	DLE	8-bit resolution			±1.0	LSB
Analog input voltage	V_{AIN}		0		V_{BGR}[Note 3]	V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. See **2.6.2 Temperature sensor/internal reference voltage characteristics**.

4. When reference voltage (–) = V_{SS}, the MAX. values are as follows.

Zero-scale error: Add ±0.35%FSR to the MAX. value when reference voltage (–) = AV_{REFM}.

Integral linearity error: Add ±0.5 LSB to the MAX. value when reference voltage (–) = AV_{REFM}.

Differential linearity error: Add ±0.2 LSB to the MAX. value when reference voltage (–) = AV_{REFM}.

2.6.2 Temperature sensor/internal reference voltage characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V_{TMPS25}	Setting ADS register = 80H, T_A = +25°C		1.05		V
Internal reference voltage	V_{BGRT}	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	F_{VTMPS}	Temperature sensor that depends on the temperature		–3.6		mV/C
Operation stabilization wait time	t_{AMP}		5			μs

2.6.3 Programmable gain amplifier

(T_A = –40 to +105°C, 2.7 V ≤ AV_{REFP} = V_{DD} ≤ 5.5 V, V_{SS} = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Input offset voltage	V_{IOPGA}					±5	±10	mV
Input voltage range	V_{IPGA}				0		0.9V_{DD}/gain	V
Gain error[Note 1]		4, 8 times					±1	%
		16 times					±1.5	%
		32 times					±2	%
Slew rate[Note 1]	SR_{RPGA}	Rising edge	4.0 V ≤ V_{DD} ≤ 5.5 V	4, 8 times	4			V/μs
				16, 32 times	1.4			V/μs
			2.7 V ≤ V_{DD} < 4.0 V	4, 8 times	1.8			V/μs
				16, 32 times	0.5			V/μs
	SR_{FPGA}	Falling edge	4.0 V ≤ V_{DD} ≤ 5.5 V	4, 8 times	3.2			V/μs
				16, 32 times	1.4			V/μs
			2.7 V ≤ V_{DD} < 4.0 V	4, 8 times	1.2			V/μs
				16, 32 times	0.5			V/μs
Operation stabilization wait time[Note 2]	t_{PGA}	4, 8 times			5			μs
		16, 32 times			10			μs

Notes 1. When V_{IPGA} = 0.1V_{DD}/gain to 0.9V_{DD}/gain.

2. Time required until a state is entered where the DC and AC specifications of the PGA are satisfied after the PGA operation has been enabled (PGAEN = 1).

Remark These characteristics apply when AV_{REFM} is selected as GND of the PGA by using the CVRVS1 bit.

2.6.4 Comparator

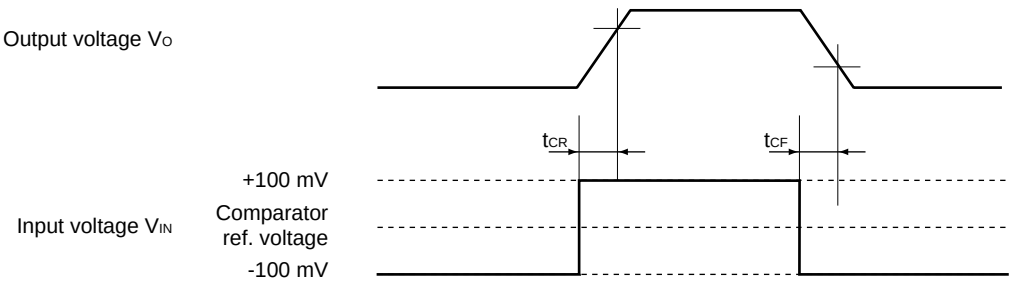
(T_A = –40 to +105°C, 2.7 V ≤ AV_{REFP} = V_{DD} ≤ 5.5 V, V_{SS} = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input offset voltage	V_{IOCMP}			±5	±40	mV
Input voltage range	V_{ICMP}	CMP0P to CMP5P	0		V_{DD}	V
		CMPCOM	0.045		0.9V_{DD}	V
Internal reference voltage deviation	ΔV_{IREF}	CmRVM register values: 7FH to 80H (m = 0 to 2)			±2	LSB
		Other than above			±1	LSB
Response time	t_{CR}, t_{CF}	Input amplitude = ±100 mV		70	150	ns
Operation stabilization wait time[Note 1]	t_{CMP}	3.3 V ≤ V_{DD} ≤ 5.5 V	1			μs
		2.7 V ≤ V_{DD} < 3.3 V	3			μs
Reference voltage stabilization wait time	t_{VR}	CVRE: 0 to 1[Note 2]	10			μs

Notes 1. Time required until a state is entered where the DC and AC specifications of the comparator are satisfied after the operation of the comparator has been enabled (CMPnEN bit = 1: n = 0 to 5)

2. Enable comparator output (CnOE bit = 1; n = 0 to 5) after enabling operation of the internal reference voltage generator (by setting the CVREm bit to 1; m = 0 to 2) and waiting for the operation stabilization time to elapse.

Remark These characteristics apply when AV_{REFP} is selected as the power supply source of the internal reference voltage by using the CVRVS0 bit, and when AV_{REFM} is selected as GND of the internal reference voltage by using the CVRVS1 bit.

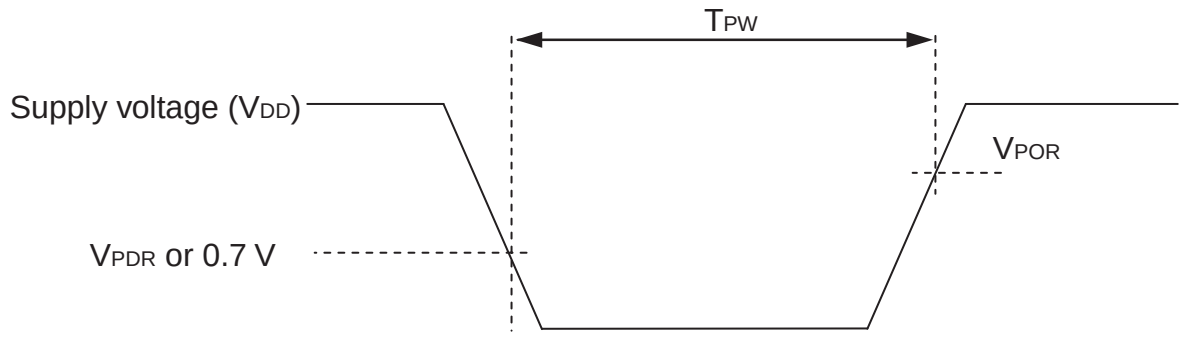


2.6.5 POR circuit characteristics

(T_A = –40 to +105°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V_{POR}	Power supply rise time	1.45	1.51	1.57	V
	V_{PDR}	Power supply fall time	1.44	1.50	1.56	V
Minimum pulse width[Note]	T_{PW}		300			μs

Note Minimum time required for a POR reset when V_{DD} exceeds below V_{PDR}. This is also the minimum time required for a POR reset from when V_{DD} exceeds below 0.7 V to when V_{DD} exceeds V_{POR} while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



2.6.6 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

(T_A = –40 to +105°C, $V_{PDR} \le V_{DD} \le 5.5$ V, V_{SS} = 0 V)

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	Supply voltage level	V_{LVD0}	Power supply rise time	3.97	4.06	4.14	V
			Power supply fall time	3.89	3.98	4.06	V
		V_{LVD1}	Power supply rise time	3.67	3.75	3.82	V
			Power supply fall time	3.59	3.67	3.74	V
		V_{LVD2}	Power supply rise time	3.06	3.13	3.19	V
			Power supply fall time	2.99	3.06	3.12	V
		V_{LVD3}	Power supply rise time	2.95	3.02	3.08	V
			Power supply fall time	2.89	2.96	3.02	V
		V_{LVD4}	Power supply rise time	2.85	2.92	2.97	V
			Power supply fall time	2.79	2.86	2.91	V
		V_{LVD5}	Power supply rise time	2.75	2.81	2.87	V
			Power supply fall time	2.70	2.75	2.81	V
Minimum pulse width		t_{LW}		300			μs
Detection delay time						300	μs

LVD Detection Voltage of Interrupt & Reset Mode

(T_A = –40 to +105°C, $V_{PDR} \le V_{DD} \le 5.5$ V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Interrupt and reset mode	V_{LVD0}	V_{POC2}, V_{POC1}, V_{POC0} = 0, 1, 1, falling reset voltage: 2.7 V		2.70	2.75	2.81	V
	V_{LVD1}	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.85	2.92	2.97	V
			Falling interrupt voltage	2.79	2.86	2.91	V
	V_{LVD2}	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.95	3.02	3.08	V
			Falling interrupt voltage	2.89	2.96	3.02	V
	V_{LVD3}	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.97	4.06	4.14	V
			Falling interrupt voltage	3.89	3.98	4.06	V

2.6.7 Supply voltage rise inclination characteristics

(T_A = –40 to +105°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Supply voltage rise	SV_{DD}				54	V/ms

Caution Keep the internal reset status by using the LVD circuit or an external reset signal until V_{DD} rises to within the operating voltage range shown in 32.4 AC Characteristics.

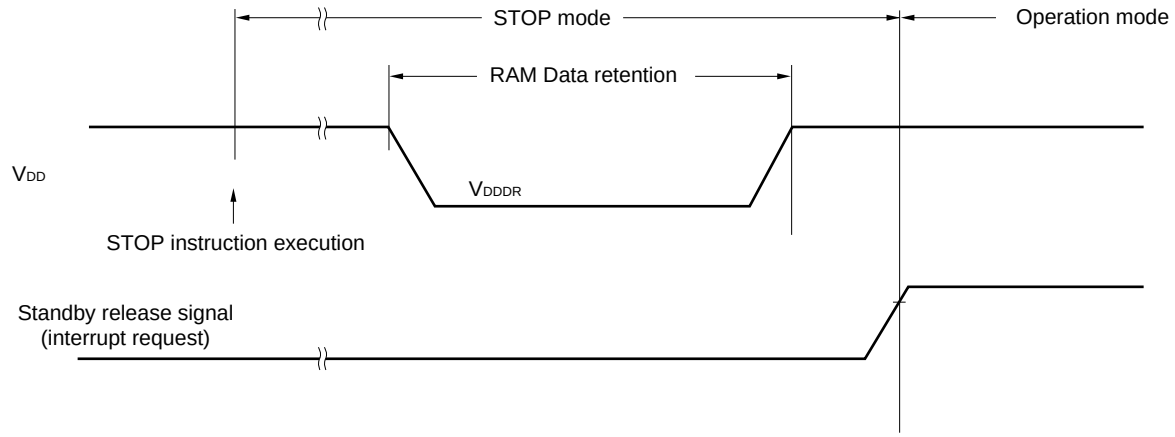
2.7 RAM Data Retention Characteristics

(T_A = –40 to +105°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage[Note 2]	V_{DDDR}		1.44[Note 1]		5.5	V

Note The value depends on the POR detection voltage. When the voltage drops, the RAM data is retained before a POR reset is effected, but RAM data is not retained when a POR reset is effected.

Caution When CPU is operated at the voltage of out of the operation voltage range, RAM data is not retained. Therefore, set STOP mode before the supplied voltage is below the operation voltage range.



2.8 Flash Memory Programming Characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	f_{CLK}	2.7 V ≤ V_{DD} ≤ 5.5 V	1		32	MHz
Number of code flash rewrites Notes 1, 2, 3	C_{erwr}	Retained for 20 years, T_A = 85°C Note 3	1,000			Times
Number of data flash rewrites Notes 1, 2, 3		Retained for 1 year, T_A = 25°C Note 3		1,000,000		
		Retained for 5 years, T_A = 85°C Note 3	100,000			
		Retained for 20 years, T_A = 85°C Note 3	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

2. When using flash memory programmer and Renesas Electronics self programming library

3. These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

2.9 Dedicated Flash Memory Programmer Communication (UART)

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

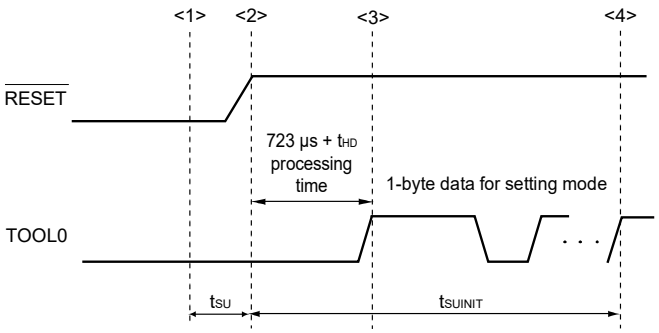
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115.2 k		1 M	bps

2.10 Timing of Entry to Flash Memory Programming Modes

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when an external reset ends until the initial communication settings are specified	t_{SUINIT}	POR and LVD reset must end before the external reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until an external reset ends	t_{SU}	POR and LVD reset must end before the external reset ends.	10			μs
How long the TOOL0 pin must be kept at the low level after a reset ends (except soft processing time)	t_{HD}	POR and LVD reset must end before the external reset ends.	1			ms

<R>



<1> The low level is input to the TOOL0 pin.
<2> The external reset ends (POR and LVD reset must end before the pin reset ends.).
<3> The TOOL0 pin is set to the high level.
<4> Complete the baud rate setting by UART reception.

Remark t_{SUINIT}: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.

t_{SU}: How long from when the TOOL0 pin is placed at the low level until an external reset ends

t_{HD}: How long to keep the TOOL0 pin at the low level from when the external and internal resets end (except soft processing time)

3. ELECTRICAL SPECIFICATIONS (M: Industrial applications, T_A = –40 to +125°C)

In this chapter, shows the electrical specifications of the target products.

Target products (M: Industrial applications): T_A = – 40 to +125°C
R5F107xxMxx

Cautions 1. The RL78/I1A has an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.

2. The pins mounted depend on the product. See 2.1 Port Function to 2.2.1 Functions for each product in the RL78/I1A User's Manual.

3. When any of these products are used at 105°C or lower, see 2. ELECTRICAL SPECIFICATIONS (T_A = –40 to +105°C).

3.1 Absolute Maximum Ratings

Absolute Maximum Ratings (T_A = 25°C) (1/2)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V_{DD}		–0.5 to +6.5	V
REGC pin input voltage	V_{IREGC}	REGC	–0.3 to +2.8 and –0.3 to V_{DD} +0.3 Note 1	V
Input voltage	V_{I1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120 to P124, P137, P147, P200 to P206, EXCLK, EXCLKS, $\overline{\text{RESET}}$	–0.3 to V_{DD} +0.3 Note 2	V
Output voltage	V_{O1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	–0.3 to V_{DD} +0.3 Note 2	V
Analog input voltage	V_{AI1}	ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19	–0.3 to V_{DD} +0.3 and –0.3 to $AV_{REF(+)}$ +0.3 Notes 2, 3	V

Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μF). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

2. Must be 6.5 V or lower.

3. Do not exceed $AV_{REF(+)}$ + 0.3 V in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remarks 1. Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

2. $AV_{REF(+)}$: + side reference voltage of the A/D converter.

3. V_{SS} : Reference voltage

Absolute Maximum Ratings (T_A = 25°C) (2/2)

Parameter	Symbols	Conditions		Ratings	Unit
Output current, high	I_{OH1}	Per pin	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	–40	mA
		Total of all pins –170 mA	P02, P03, P40, P120	–70	mA
			P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206	–100	mA
	I_{OH2}	Per pin	P20 to P22, P24 to P27	–0.5	mA
		Total of all pins		–2	mA
Output current, low	I_{OL1}	Per pin	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	40	mA
		Total of all pins 170 mA	P02, P03, P40, P120	70	mA
			P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206	100	mA
	I_{OL2}	Per pin	P20 to P22, P24 to P27	1	mA
		Total of all pins		5	mA
Operating ambient temperature	T_A	In normal operation mode		–40 to +125	°C
		In flash memory programming mode		–40 to +105	
Storage temperature	T_{stg}			–65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

3.2 Oscillator Characteristics

3.2.1 X1, XT1 oscillator characteristics

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock frequency (f_X)Note	Ceramic resonator/ crystal resonator		1.0		20.0	MHz
XT1 clock frequency (f_{XT})Note	Crystal resonator		32	32.768	35	kHz

Note Indicates only permissible oscillator frequency ranges. See **AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution **Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.**

Remark When using the X1 oscillator and XT1 oscillator, see 5.4 System Clock Oscillator in the RL78/I1A User's Manual.

3.2.2 On-chip oscillator characteristics

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Oscillators	Parameters	Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency[Note 1]	f_{IH}		1		32	MHz
High-speed on-chip oscillator clock frequency accuracy[Note 2]		T_A = –20 to 85°C	–1		+1	%
		T_A = –40 to 105°C	–1.5		+1.5	%
		T_A = –40 to 125°C When 16 MHz selected	–2		+2	%
Low-speed on-chip oscillator clock frequency	f_{IL}			15		kHz
Low-speed on-chip oscillator clock frequency accuracy			–15		+15	%

Notes 1. Frequency can be selected in a high-speed on-chip oscillator. Selected by bits 0 to 3 of option byte (000C2H/010C2H).

2. This indicates the oscillator characteristics only. See **AC Characteristics** for instruction execution time.

Remark When using the device at an ambient temperature that exceeds T_A = 105°C, the selectable oscillation frequency is 16 MHz max.

3.2.3 PLL characteristics

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
PLL input clock frequency[Note]	f_{PLLIN}	High-speed system clock is selected (f_{MX} = 4 MHz)	3.92	4.00	4.08	MHz
		High-speed on-chip oscillator clock is selected (f_{IH} = 4 MHz)	3.92	4.00	4.08	MHz
PLL output clock frequency[Note]	f_{PLL}		f_{PLLIN} × 16			MHz

Note This only indicates the oscillator characteristics. See **AC Characteristics** for instruction execution time.

Remark When using the device at an ambient temperature that exceeds T_A = 105°C, only 16 MHz (f_{PLL} × 1/4) can be selected as the CPU operating frequency.

3.3 DC Characteristics

3.3.1 Pin characteristics

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high[Note 1]	I_{OH1}	Per pin for P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V			–3.0[Note 2]	mA
			2.7 V ≤ V_{DD} < 4.0 V			–1.0	mA
		Total of P02, P03, P40, P120 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			–9.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			–3.0	mA
		Total of P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			–21.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			–6.0	mA
		Total of all pins (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			–21.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			–9.0	mA
	I_{OH2}	Per pin for P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V			–0.1[Note 2]	mA
		Total of all pins (When duty ≤ 70%[Note 3])	2.7 V ≤ V_{DD} ≤ 5.5 V			–0.4	mA

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from the V_{DD} pin to an output pin.

2. However, do not exceed the total current value.

3. Specification under conditions where the duty factor ≤ 70%.
The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (I_{OH} × 0.7)/(n × 0.01)

<Example> Where n = 80% and I_{OH} = –10.0 mA

Total output current of pins = (–10.0 × 0.7)/(80 × 0.01) ≅ –8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P02, P10 to P12 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low[Note 1]	I_{OL1}	Per pin for P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V			8.5[Note 2]	mA
			2.7 V ≤ V_{DD} < 4.0 V			1.5[Note 2]	mA
		Total of P02, P03, P40, P120 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			20.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			5.0	mA
		Total of P05, P06, P10 to P12, P30, P31, P75 to P77, P147, P200 to P206 (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			20.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			10.0	mA
		Total of all pins (When duty ≤ 70%[Note 3])	4.0 V ≤ V_{DD} ≤ 5.5 V			40.0	mA
			2.7 V ≤ V_{DD} < 4.0 V			15.0	mA
	I_{OL2}	Per pin for P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V			0.4[Note 2]	mA
		Total of all pins (When duty ≤ 70%[Note 3])	2.7 V ≤ V_{DD} ≤ 5.5 V			1.6	mA

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the V_{SS} pin.

2. However, do not exceed the total current value.

3. Specification under conditions where the duty factor ≤ 70%.
The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (I_{OL} × 0.7)/(n × 0.01)

<Example> Where n = 80% and I_{OL} = –10.0 mA

Total output current of pins = (–10.0 × 0.7)/(80 × 0.01) ≅ –8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V_{IH1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120 to P124, P137, P147, P200 to P206, EXCLK, EXCLKS, $\overline{\text{RESET}}$	Normal input buffer	0.8V_{DD}		V_{DD}	V
	V_{IH2}	P03, P10, P11	TTL input buffer 4.0 V ≤ V_{DD} ≤ 5.5 V	2.1		V_{DD}	V
			TTL input buffer 3.3 V ≤ V_{DD} < 4.0 V	2.0		V_{DD}	V
			TTL input buffer 2.7 V ≤ V_{DD} < 3.3 V	1.5		V_{DD}	V
Input voltage, low	V_{IL1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120 to P124, P137, P147, P200 to P206, EXCLK, EXCLKS, $\overline{\text{RESET}}$	Normal input buffer	0		0.2V_{DD}	V
	V_{IL2}	P03, P10, P11	TTL input buffer 4.0 V ≤ V_{DD} ≤ 5.5 V	0		0.8	V
			TTL input buffer 3.3 V ≤ V_{DD} < 4.0 V	0		0.5	V
			TTL input buffer 2.7 V ≤ V_{DD} < 3.3 V	0		0.32	V

Caution The maximum value of V_{IH} of pins P02, P10 to P12 is V_{DD}, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	V_{OH1}	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V, I_{OH1} = –3.0 mA	V_{DD} – 0.7			V
			2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OH1} = –1.0 mA	V_{DD} – 0.5			V
	V_{OH2}	P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OH2} = –100 μA	V_{DD} – 0.5			V
Output voltage, low	V_{OL1}	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	4.0 V ≤ V_{DD} ≤ 5.5 V, I_{OL1} = 8.5 mA			0.7	V
			4.0 V ≤ V_{DD} ≤ 5.5 V, I_{OL1} = 4.0 mA			0.4	V
			2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OL1} = 1.5 mA			0.4	V
	V_{OL2}	P20 to P22, P24 to P27	2.7 V ≤ V_{DD} ≤ 5.5 V, I_{OL2} = 400 μA			0.4	V

Caution P02, P10 to P12 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Input leakage current, high	I_{LIH1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120, P137, P147, P200 to P206, RESET	$V_I = V_{DD}$				1	μA
	I_{LIH2}	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	$V_I = V_{DD}$	In input port or external clock input			1	μA
				In resonator connection			10	μA
Input leakage current, low	I_{LIL1}	P02, P03, P05, P06, P10 to P12, P20 to P22, P24 to P27, P30, P31, P40, P75 to P77, P120, P137, P147, P200 to P206, RESET	$V_I = V_{SS}$				–1	μA
	I_{LIL2}	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	$V_I = V_{SS}$	In input port or external clock input			–1	μA
				In resonator connection			–10	μA
On-chip pull-up resistance	R_U	P02, P03, P05, P06, P10 to P12, P30, P31, P40, P75 to P77, P120, P147, P200 to P206	$V_I = V_{SS}$, In input port		10	20	100	kΩ

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

3.3.2 Supply current characteristics

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V) (1/2)

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Supply current Note 1	I_{DD1}	Operating mode	HS (high-speed main) mode Note 5	f_{IH} = 16 MHz Note 3	V_{DD} = 5.0 V		2.9	4.8	mA
					V_{DD} = 3.0 V		2.9	4.8	mA
			HS (high-speed main) mode Note 5	f_{MX} = 20 MHz Note 2, V_{DD} = 5.0 V	Square wave input		3.2	5.6	mA
					Resonator connection		3.3	5.7	mA
				f_{MX} = 20 MHz Note 2, V_{DD} = 3.0 V	Square wave input		3.2	5.6	mA
					Resonator connection		3.3	5.7	mA
				f_{MX} = 10 MHz Note 2, V_{DD} = 5.0 V	Square wave input		2.0	3.3	mA
					Resonator connection		2.0	3.3	mA
				f_{MX} = 10 MHz Note 2, V_{DD} = 3.0 V	Square wave input		2.0	3.3	mA
					Resonator connection		2.0	3.3	mA
			HS (high-speed main) mode Note 5	f_{IH} = 4 MHz Note 3 f_{PLL} = 64 MHz, f_{CLK} = 16 MHz	V_{DD} = 5.0 V		3.3	6.5	mA
					V_{DD} = 3.0 V		3.3	6.5	mA
			Subsystem clock operation	f_{SUB} = 32.768 kHz Note 4 T_A = –40°C	Square wave input		4.2	6.0	μA
					Resonator connection		4.4	6.2	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +25°C	Square wave input		4.2	6.0	μA
					Resonator connection		4.4	6.2	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +50°C	Square wave input		4.3	7.2	μA
					Resonator connection		4.5	7.4	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +70°C	Square wave input		4.4	8.1	μA
					Resonator connection		4.6	8.3	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +85°C	Square wave input		5.2	11.4	μA
					Resonator connection		5.4	11.6	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +105°C	Square wave input		6.9	20.8	μA
					Resonator connection		7.1	21.0	μA
				f_{SUB} = 32.768 kHz Note 4 T_A = +125°C	Square wave input		11.1	51.2	μA
					Resonator connection		11.3	51.4	μA

(**Notes** and **Remarks** are listed on the next page.)

Notes 1. Total current flowing into V_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD} or V_{SS}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, comparator, programmable gain amplifier, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

2. When high-speed on-chip oscillator and subsystem clock are stopped.

3. When high-speed system clock and subsystem clock are stopped.

4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.

5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 20 MHz

Remarks 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

2. f_{IH}: High-speed on-chip oscillator clock frequency

3. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

4. Except subsystem clock operation, temperature condition of the TYP. value is T_A = 25°C

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V) (2/2)

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Supply current Note 1	I_{DD2} Note 2	HALT mode	HS (high-speed main) mode Note 7	f_{IH} = 16 MHz Note 4	V_{DD} = 5.0 V		0.50	2.0	mA
					V_{DD} = 3.0 V		0.50	2.0	mA
			HS (high-speed main) mode Note 7	f_{MX} = 20 MHz Note 3, V_{DD} = 5.0 V	Square wave input		0.40	2.2	mA
					Resonator connection		0.50	2.3	mA
				f_{MX} = 20 MHz Note 3, V_{DD} = 3.0 V	Square wave input		0.40	2.2	mA
					Resonator connection		0.50	2.3	mA
				f_{MX} = 10 MHz Note 3, V_{DD} = 5.0 V	Square wave input		0.24	1.22	mA
					Resonator connection		0.30	1.28	mA
				f_{MX} = 10 MHz Note 3, V_{DD} = 3.0 V	Square wave input		0.24	1.22	mA
					Resonator connection		0.30	1.28	mA
			HS (high-speed main) mode Note 7	f_{IH} = 4 MHz Note 4 f_{PLL} = 64 MHz, f_{CLK} = 16 MHz	V_{DD} = 5.0 V		0.95	3.7	mA
					V_{DD} = 3.0 V		0.95	3.7	mA
			Subsystem clock operation	f_{SUB} = 32.768 kHz Note 5 T_A = –40°C	Square wave input		0.28	0.70	μA
					Resonator connection		0.47	0.89	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +25°C	Square wave input		0.33	0.70	μA
					Resonator connection		0.52	0.89	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +50°C	Square wave input		0.41	1.90	μA
					Resonator connection		0.60	2.09	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +70°C	Square wave input		0.54	2.80	μA
					Resonator connection		0.73	2.99	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +85°C	Square wave input		1.27	6.10	μA
					Resonator connection		1.46	6.29	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +105°C	Square wave input		3.04	15.5	μA
					Resonator connection		3.23	15.7	μA
				f_{SUB} = 32.768 kHz Note 5 T_A = +125°C	Square wave input		7.20	45.2	μA
					Resonator connection		7.53	45.5	μA
	I_{DD3} Note 6	STOP mode Note 8	T_A = –40°C				0.18	0.50	μA
			T_A = +25°C				0.23	0.50	μA
			T_A = +50°C				0.27	1.70	μA
			T_A = +70°C				0.44	2.60	μA
			T_A = +85°C				1.17	5.90	μA
			T_A = +105°C				2.94	15.3	μA
			T_A = +125°C				7.14	45.1	μA

(**Notes** and **Remarks** are listed on the next page.)

Notes 1. Total current flowing into V_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD} or V_{SS}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, comparator, programmable gain amplifier, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

2. During HALT instruction execution by flash memory.

3. When high-speed on-chip oscillator and subsystem clock are stopped.

4. When high-speed system clock and subsystem clock are stopped.

5. When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.

6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.

7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 20 MHz

8. Regarding the value for current operate the subsystem clock in STOP mode, refer to that in HALT mode.

Remarks 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

2. f_{IH}: High-speed on-chip oscillator clock frequency

3. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is T_A = 25°C

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	I_{FIL} Note 1				0.20		μA
RTC operating current	I_{RTC} Notes 1, 2, 3				0.02		μA
12-bit interval timer operating current	I_{IT} Notes 1, 2, 4				0.02		μA
Watchdog timer operating current	I_{WDT} Notes 1, 2, 5	f_{IL} = 15 kHz			0.22		μA
A/D converter operating current	I_{ADC} Notes 1, 6	When conversion at maximum speed	Normal mode, AV_{REFP} = V_{DD} = 5.0 V		1.3	1.7	mA
A/D converter reference voltage current	I_{ADREF} Note 1				75.0		μA
Temperature sensor operating current	I_{TMPS} Note 1				75.0		μA
LVD operating current	I_{LVD} Notes 1, 7				0.08		μA
Self-programming operating current	I_{FSP} Notes 1, 8				2.5	12.2	mA
Programmable gain amplifier operating current	I_{PGA} Note 9		AV_{REFP} = V_{DD} = 5.0 V		0.21	0.37	mA
			AV_{REFP} = V_{DD} = 3.0 V		0.18	0.35	mA
Comparator operating current	I_{CMP} Note 10	When one comparator channel is operating	AV_{REFP} = V_{DD} = 5.0 V		41.4	74	μA
			AV_{REFP} = V_{DD} = 3.0 V		37.2	71	μA
	I_{VREF}	When one internal reference voltage circuit is operating	AV_{REFP} = V_{DD} = 5.0 V		14.8	31	μA
			AV_{REFP} = V_{DD} = 3.0 V		8.9	24	μA
Programmable gain amplifier/ comparator reference current source	I_{IREF} Note 11		AV_{REFP} = V_{DD} = 5.0 V		3.2	6.1	μA
			AV_{REFP} = V_{DD} = 3.0 V		2.9	4.9	μA
BGO operating current	I_{BGO} Note 12				2.50	12.2	mA
SNOOZE operating current	I_{SNOZ} Note 1	A/D converter operation	The mode is performed Note 13		0.50	1.10	mA
			The A/D conversion operations are performed, Normal mode, AV_{REFP} = V_{DD} = 5.0 V		1.20	2.17	mA
		CSI/UART operation			0.70	1.27	mA

(**Notes** and **Remarks** are listed on the next page.)

Notes 1. Current flowing to the V_{DD}.

2. When the high-speed on-chip oscillator and high-speed system clock are stopped.

3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either I_{DD1} or I_{DD2}, and I_{RTC}, when the real-time clock is operating in operating mode or in HALT mode. When the low-speed on-chip oscillator is selected, I_{FIL} should be added. I_{DD2} subsystem clock operation includes the operational current of the real-time clock.

4. Current flowing only to the 12-bit interval timer (excluding the operating current of the XT1 oscillator and f_{IL} operating current). The current of the RL78 microcontrollers is the sum of the values of either I_{DD1} or I_{DD2}, and I_{IT}, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, I_{FIL} should be added.

5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3}, and I_{WDT}, when the watchdog timer is operating.

6. Current flowing only to the A/D converter. The supply current value of the RL78 microcontrollers is the sum of I_{DD1} or I_{DD2} and I_{ADC}, when the A/D converter is operating in operating mode or in HALT mode.

7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3} and I_{LVD} when the LVD circuit is in operation.

8. Current flowing during self-programming operation.

9. Current flowing only to the programmable gain amplifier. The supply current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3}, and I_{PGA}, when the programmable gain amplifier is operating in operating mode or in HALT mode.

10. Current flowing only to the comparator. The supply current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3}, and I_{CMP}, when the comparator is operating.

11. This is the current required to flow to V_{DD} pin of the current circuit that is used as the programmable gain amplifier and the comparator.

12. Current flowing only during data flash rewrite.

13. See **21.3.3 SNOOZE mode in the RL78/I1A User's Manual** for shift time to the SNOOZE mode.

Remarks 1. f_{IL}: Low-speed on-chip oscillator clock frequency

2. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

3. f_{CLK}: CPU/peripheral hardware clock frequency

4. Temperature condition of the TYP. value is T_A = 25°C

5. Example of calculating current value when using programmable gain amplifier and comparator.

Examples 1) TYP. operating current value when three comparator channels, one internal reference voltage generator, and PGA are operating (when AV_{REFP} = V_{DD} = 5.0 V)

$I_{CMP} \times 3 + I_{VREF} + I_{PGA} + I_{IREF}$

= 41.4 [μA] × 3 + 14.8 [μA] × 1 + 210 [μA] + 3.2 [μA]

= 352.2 [μ A]

Examples 2) TYP. operating current value when using two comparator channels, without using internal reference voltage generator (when AV_{REFP} = V_{DD} = 5.0 V)

$I_{CMP} \times 2 + I_{IREF}$

= 41.4 [μA] × 2 + 3.2 [μA]

= 86.0 [μA]

3.4 AC Characteristics

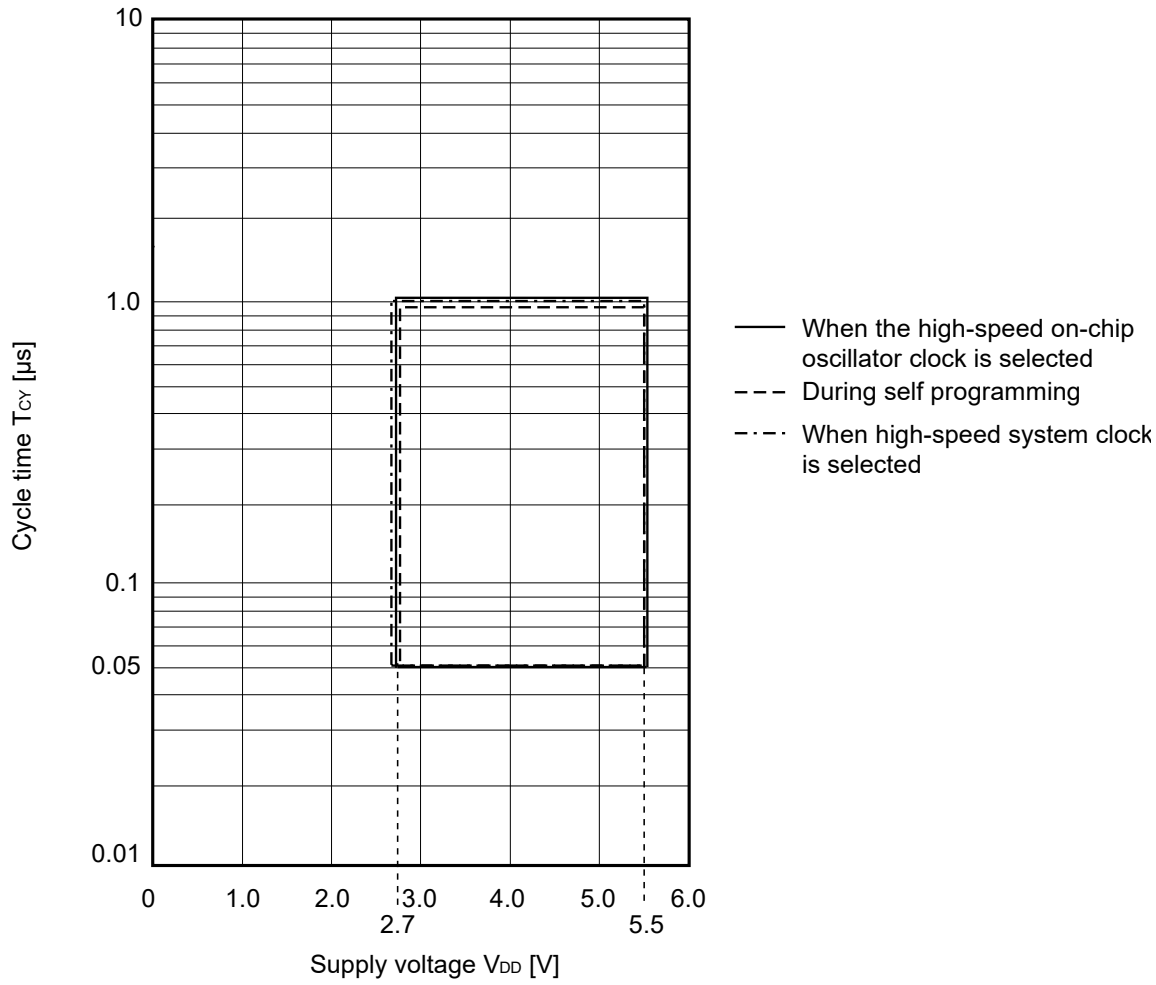
(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum instruction execution time)	T_{CY}	Main system clock (f_{MAIN}) operation	HS (high-speed main) mode		0.05		1	μs
		Subsystem clock (f_{SUB}) operation			28.5	30.5	31.3	μs
		In the self programming mode	HS (high-speed main) mode	T_A = –40 to +105°C	0.05		1	μs
External system clock frequency	f_{EX}				1.0		20.0	MHz
	f_{EXS}				32		35	kHz
External system clock input high-level width, low-level width	t_{EXH}, t_{EXL}				24			ns
	t_{EXHS}, t_{EXLS}				13.7			μs
TI03, TI05, TI06, TI07 input high-level width, low-level width	t_{TIH}, t_{TIL}				2/f_{MCK}+10			ns
TO03, TO05, TO06, TKBO00, TKBO01, TKBO10, TKBO11, TKBO20, TKBO21, TKCO00 to TKCO05 output frequency (When duty = 50%)	f_{TO}	HS (high-speed main) mode		4.0 V ≤ V_{DD} ≤ 5.5 V			5	MHz
				2.7 V ≤ V_{DD} < 4.0 V			4	MHz
Interrupt input high-level width, low-level width	t_{INTH}, t_{INTL}	INTP0, INTP3, INTP4, INTP9 to INTP11, INTP20 to INTP23		2.7 V ≤ V_{DD} ≤ 5.5 V	1			μs
$\overline{RESET}$ low-level width	t_{RSL}				10			μs

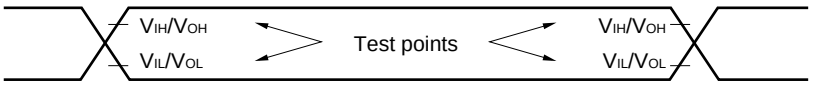
Remark f_{MCK}: Timer array unit operation clock frequency
(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

Minimum Instruction Execution Time during Main System Clock Operation

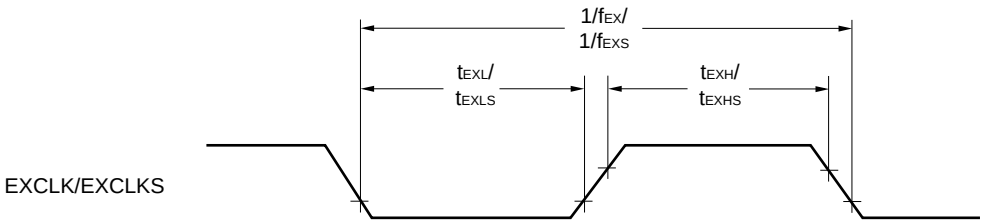
T_{CY} vs V_{DD} (HS (high-speed main) mode)



AC Timing Test Points

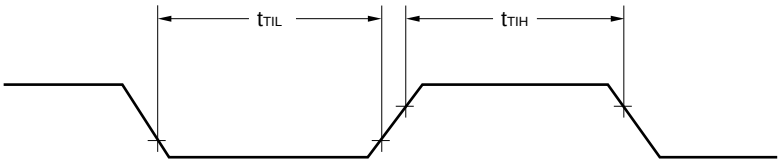


External System Clock Timing

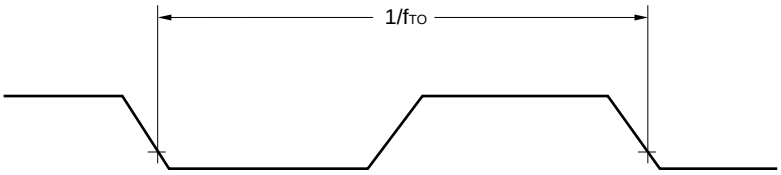


TI/TO Timing

TI03, TI05, TI06, TI07

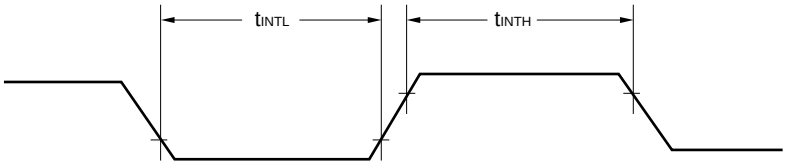


TO03, TO05, TO06, TKBO00, TKBO01, TKBO10, TKBO11, TKBO20, TKBO21, TKCO00 to TKCO05



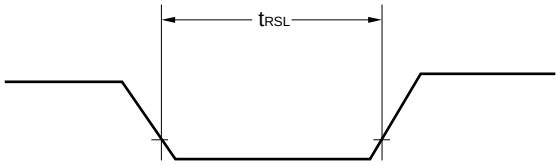
Interrupt Request Input Timing

INTP0, INTP3, INTP4, INTP9 to INTP11, INTP20 to INTP23



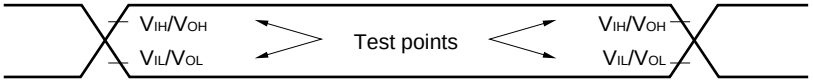
$\overline{\text{RESET}}$ Input Timing

$\overline{\text{RESET}}$



3.5 Peripheral Functions Characteristics

AC Timing Test Points



3.5.1 Serial array unit 0, 4 (UART0, UART1, CSI00, DALI/UART4)

(1) During communication at same potential (UART mode)

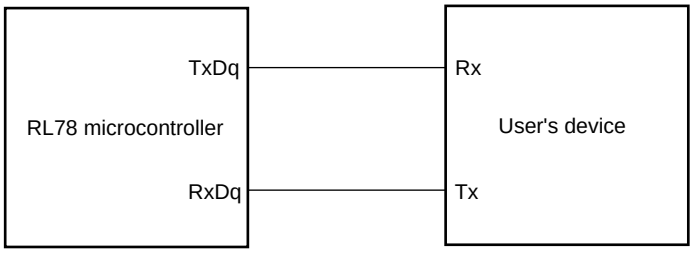
(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
Transfer rate[Note 1]				f_{MCK}/6	bps
		Theoretical value of the maximum transfer rate f_{MCK} = f_{CLK}[Note 2]		3.3	Mbps

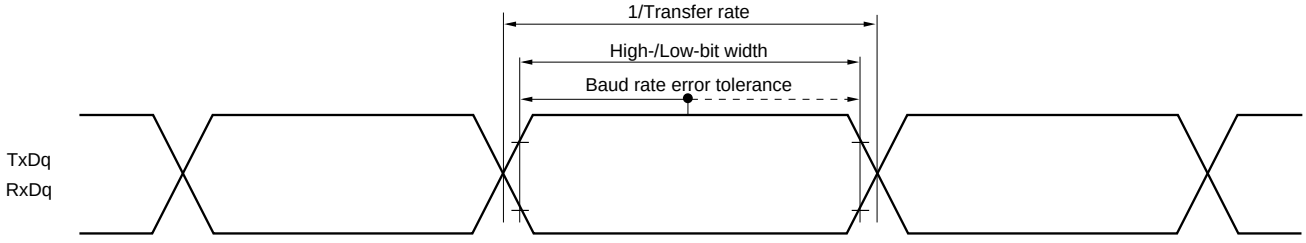
Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The operating frequencies of the CPU/peripheral hardware clock (f_{CLK}) are:
HS (high-speed main) mode: 20 MHz (2.7 V ≤ V_{DD} ≤ 5.5 V)

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

2. f_{MCK}: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03))

(2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output)

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		Unit
				MIN.	MAX.	
SCKp cycle time	t_{KCY1}	$t_{KCY1} \geq 4/f_{CLK}$	4.0 V ≤ V_{DD} ≤ 5.5 V	250		ns
			2.7 V ≤ V_{DD} ≤ 5.5 V	500		ns
SCKp high-/low-level width	t_{KH1}, t_{KL1}	4.0 V ≤ V_{DD} ≤ 5.5 V		$t_{KCY1}/2 - 20$		ns
		2.7 V ≤ V_{DD} ≤ 5.5 V		$t_{KCY1}/2 - 40$		ns
SIp setup time (to SCKp↑)Note 1	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V		80		ns
		2.7 V ≤ V_{DD} ≤ 5.5 V		80		ns
SIp hold time (from SCKp↑)Note 2	t_{KSI1}			40		ns
Delay time from SCKp↓ to SOp outputNote 3	t_{KSO1}	C = 30 pFNote 4			80	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

4. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

2. f_{MCK}: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))

(3) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input)

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		Unit
				MIN.	MAX.	
SCKp cycle time[Note 5]	t_{KCY2}	4.0 V ≤ V_{DD} ≤ 5.5 V	f_{MCK} ≤ 20 MHz	6/f_{MCK}		ns
		2.7 V ≤ V_{DD} ≤ 5.5 V	16 MHz < f_{MCK}	8/f_{MCK}		ns
			f_{MCK} ≤ 16 MHz	6/f_{MCK}		ns
SCKp high-/low-level width	t_{KH2}, t_{KL2}			t_{KCY2}/2		ns
SIp setup time (to SCKp↑)[Note 1]	t_{SIK2}			1/f_{MCK}+40		ns
SIp hold time (from SCKp↑)[Note 2]	t_{KSI2}			1/f_{MCK}+60		ns
Delay time from SCKp↓ to SOp output[Note 3]	t_{KSO2}	C = 30 pF[Note 4]			2/f_{MCK}+80	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

4. C is the load capacitance of the SOp output lines.

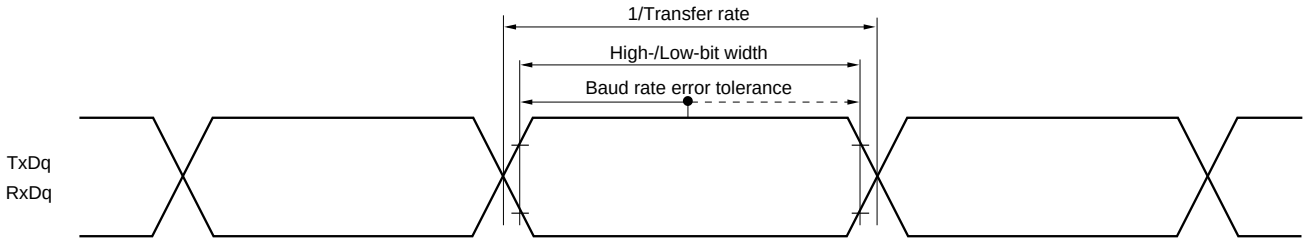
5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

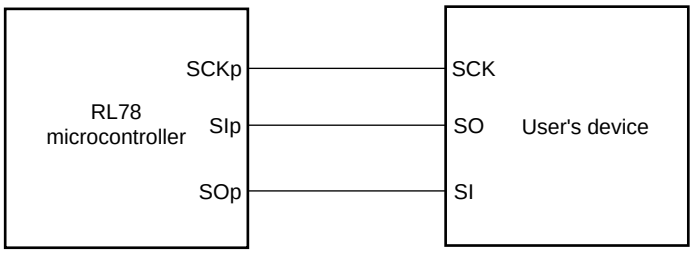
Remarks 1. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

2. f_{MCK}: Serial array unit operation clock frequency

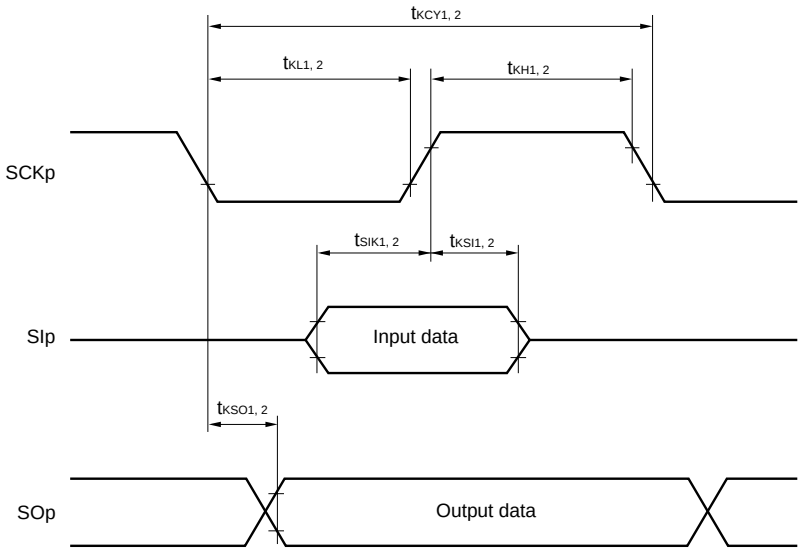
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))



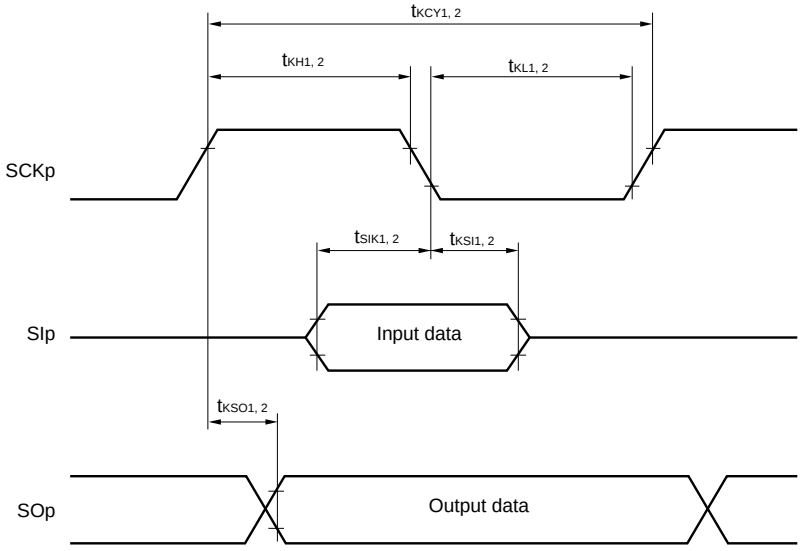
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00)

2. m: Unit number, n: Channel number (mn = 00)

(4) Communication at different potential (2.5 V, 3 V) (UART mode) (1/2)

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions			HS (high-speed main) Mode		Unit
					MIN.	MAX.	
Transfer rate		Reception	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V			f_{MCK}/6 Note 1	bps
				Theoretical value of the maximum transfer rate f_{MCK} = f_{CLK} Note 2		3.3	Mbps
			2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V			f_{MCK}/6 Note 1	bps
				Theoretical value of the maximum transfer rate f_{MCK} = f_{CLK} Note 2		3.3	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The operating frequencies of the CPU/peripheral hardware clock (f_{CLK}) are:
HS (high-speed main) mode: 20 MHz (2.7 V ≤ V_{DD} ≤ 5.5 V)

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. V_b[V]: Communication line voltage

2. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

3. f_{MCK}: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03)

(4) Communication at different potential (2.5 V, 3 V) (UART mode) (2/2)

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions			HS (high-speed main) Mode		Unit
					MIN.	MAX.	
Transfer rate		Transmission	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V			**Note 1**	bps
				Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 1.4 kΩ, V_b = 2.7 V		2.8 Note 2	Mbps
			2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V			**Note 3**	bps
				Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 2.7 kΩ, V_b = 2.3 V		1.2 Note 4	Mbps

Notes 1. The smaller maximum transfer rate derived by using f_{MCK}/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V ≤ V_{DD} ≤ 5.5 V and 2.7 V ≤ V_b ≤ 4.0 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \text{ [\%]}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

2. This value as an example is calculated when the conditions described in the “Conditions” column are met. See **Note 1** above to calculate the maximum transfer rate under conditions of the customer.

3. The smaller maximum transfer rate derived by using f_{MCK}/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V ≤ V_{DD} < 4.0 V and 2.3 V ≤ V_b ≤ 2.7 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \text{ [\%]}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

4. This value as an example is calculated when the conditions described in the “Conditions” column are met. See **Note 3** above to calculate the maximum transfer rate under conditions of the customer.

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. R_b[Ω]: Communication line (TxDq) pull-up resistance,
C_b[F]: Communication line (TxDq) load capacitance, V_b[V]: Communication line voltage

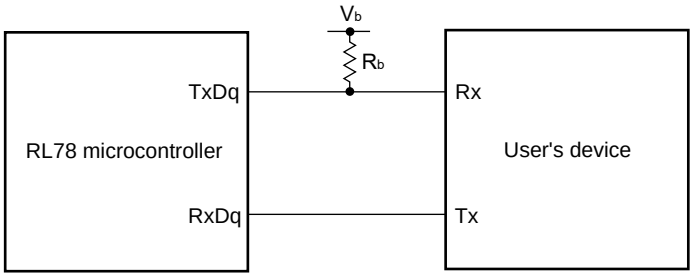
2. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

3. f_{MCK}: Serial array unit operation clock frequency

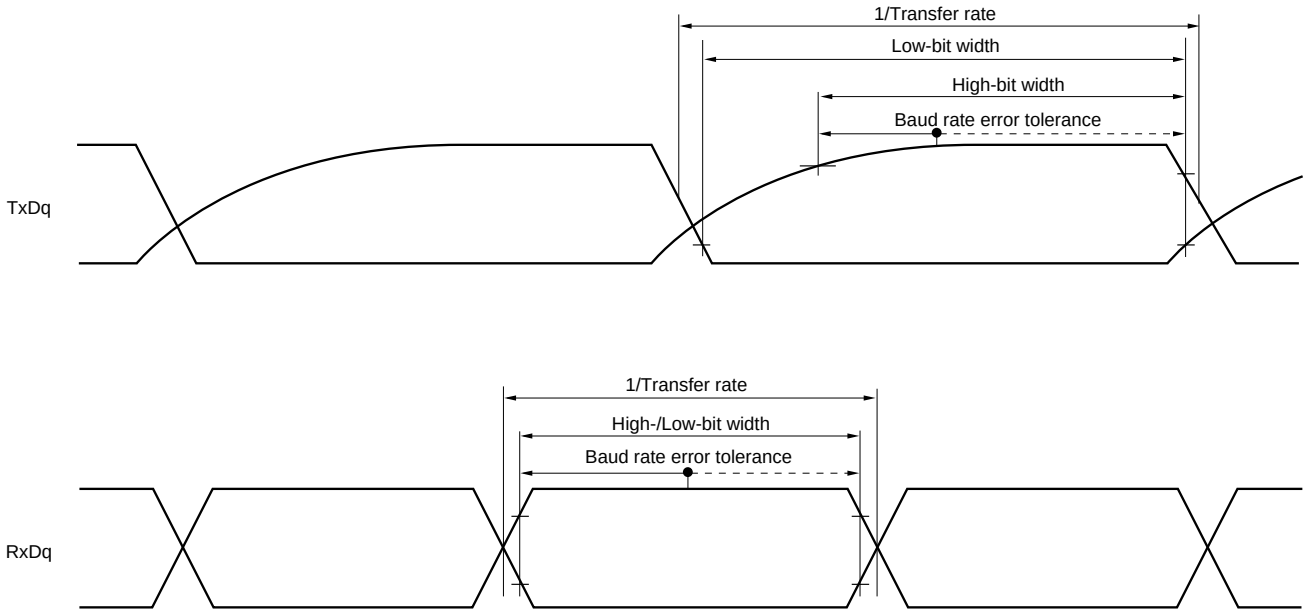
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03))

UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)



Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. R_b[Ω]: Communication line (TxDq) pull-up resistance, V_b[V]: Communication line voltage

2. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 1)

(5) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		Unit
				MIN.	MAX.	
SCKp cycle time	t_{KCY1}	$t_{KCY1} \geq 4/f_{CLK}$	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ	600		ns
			2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ	1000		ns
SCKp high-level width	t_{KH1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		t_{KCY1}/2 – 80		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		t_{KCY1}/2 – 170		ns
SCKp low-level width	t_{KL1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		t_{KCY1}/2 – 28		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		t_{KCY1}/2 – 40		ns
SIp setup time (to SCKp↑)[Note 1]	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		160		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		250		ns
SIp hold time (from SCKp↑)[Note 1]	t_{KSI1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		40		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		40		ns
Delay time from SCKp↓ to SOp output[Note 1]	t_{KSO1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ			160	ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ			250	ns
SIp setup time (to SCKp↓)[Note 2]	t_{SIK1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		80		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		80		ns
SIp hold time (from SCKp↓)[Note 2]	t_{KSI1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ		40		ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		40		ns
Delay time from SCKp↑ to SOp output[Note 2]	t_{KSO1}	4.0 V ≤ V_{DD} ≤ 5.5 V, 2.7 V ≤ V_b ≤ 4.0 V, C_b = 30 pF, R_b = 1.4 kΩ			80	ns
		2.7 V ≤ V_{DD} < 4.0 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ			80	ns

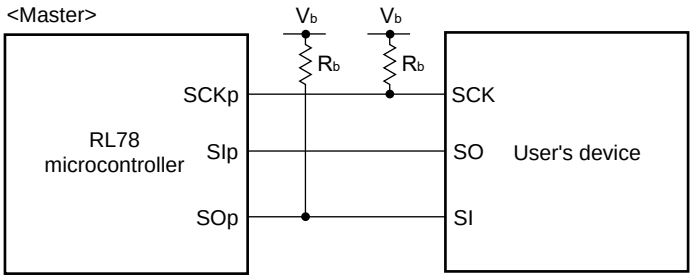
Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

(**Caution** and **Remarks** are listed on the next page.)

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

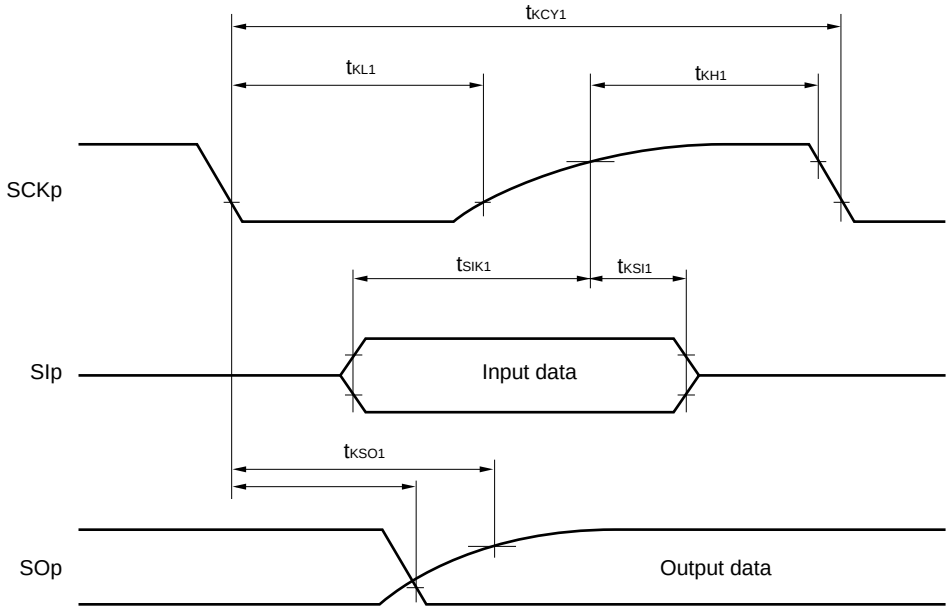
CSI mode connection diagram (during communication at different potential)



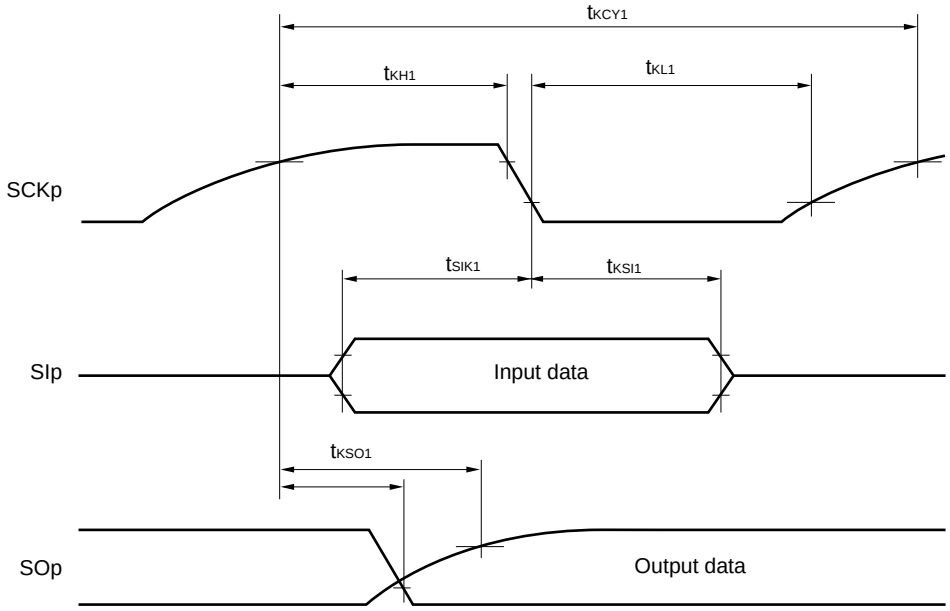
Remarks 1. R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage

2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

CSI mode serial transfer timing (master mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (master mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

(6) DALI/UART4 mode

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
Transfer rate				f_{MCK}/12	bps
		Maximum transfer rate theoretical value f_{CLK} = 20 MHz, f_{MCK} = f_{CLK}		1.6	Mbps

Remark f_{MCK}: Operation clock frequency of DALI/UART.

(Operation clock to be set by the serial clock select register 4 (SPS4).)

3.5.2 Serial interface IICA

(1) I^2C standard mode

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
SCLA0 clock frequency	f_{SCL}	Standard mode: f_{CLK} ≥ 1 MHz	0	100	kHz
Setup time of restart condition	$t_{SU:STA}$		4.7		μs
Hold time[Note 1]	$t_{HD:STA}$		4.0		μs
Hold time when SCLA0 = “L”	t_{LOW}		4.7		μs
Hold time when SCLA0 = “H”	t_{HIGH}		4.0		μs
Data setup time (reception)	$t_{SU:DAT}$		250		ns
Data hold time (transmission)[Note 2]	$t_{HD:DAT}$		0	3.45	μs
Setup time of stop condition	$t_{SU:STO}$		4.0		μs
Bus-free time	t_{BUF}		4.7		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of $t_{HD:DAT}$ is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Remark The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: C_b = 400 pF, R_b = 2.7 kΩ

(2) I^2C fast mode

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
SCLA0 clock frequency	f_{SCL}	fast mode: f_{CLK} ≥ 3.5 MHz	0	400	kHz
Setup time of restart condition	$t_{SU:STA}$		0.6		μs
Hold time[Note 1]	$t_{HD:STA}$		0.6		μs
Hold time when SCLA0 = “L”	t_{LOW}		1.3		μs
Hold time when SCLA0 = “H”	t_{HIGH}		0.6		μs
Data setup time (reception)	$t_{SU:DAT}$		100		ns
Data hold time (transmission)[Note 2]	$t_{HD:DAT}$		0	0.9	μs
Setup time of stop condition	$t_{SU:STO}$		0.6		μs
Bus-free time	t_{BUF}		1.3		μs

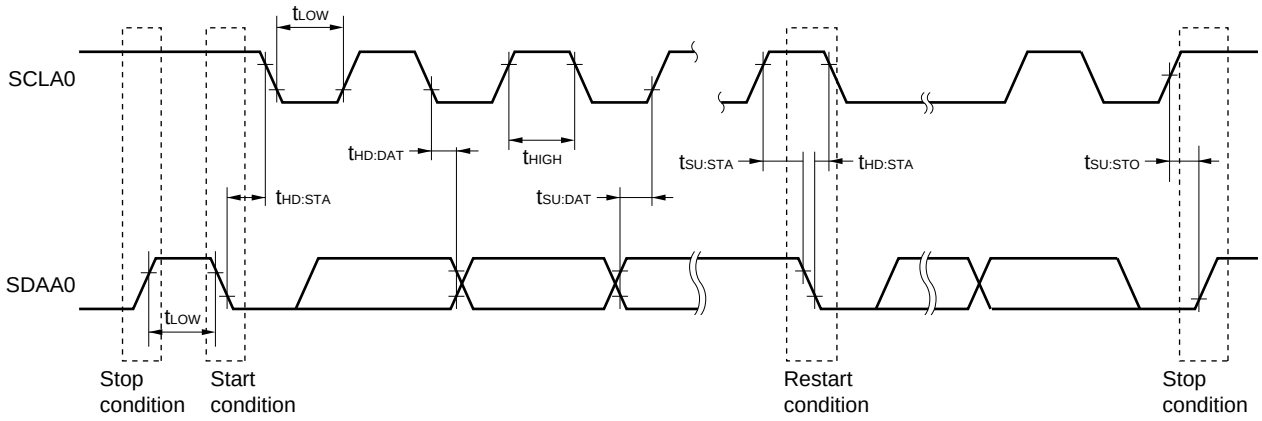
Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of $t_{HD:DAT}$ is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Remark The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

fast mode: C_b = 320 pF, R_b = 1.1 kΩ

IICA serial transfer timing



3.6 Analog Characteristics

3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel	Reference Voltage		
	Reference voltage (+) = AV_{REFP} Reference voltage (–) = AV_{REFM}	Reference voltage (+) = V_{DD} Reference voltage (–) = V_{SS}	Reference voltage (+) = V_{BGR} Reference voltage (–) = AV_{REFM}
ANI0 to ANI2, ANI4 to ANI7	See **3.6.1 (1)**.	See **3.6.1 (3)**.	See **3.6.1 (4)**.
ANI16 to ANI19	See **3.6.1 (2)**.		
Internal reference voltage Temperature sensor output voltage	See **3.6.1 (1)**.		–

(1) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target ANI pin: ANI2, ANI4 to ANI7, internal reference voltage, and temperature sensor output voltage

(T_A = –40 to +125°C, 2.7 V ≤ AV_{REFP} ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = AV_{REFP}, Reference voltage (–) = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error[Note 1]	AINL	10-bit resolution AV_{REFP} = V_{DD}[Note 3]			1.2	±3.5	LSB
Conversion time	t_{CONV}	10-bit resolution Target pin: ANI2, ANI4 to ANI7	3.6 V ≤ V_{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.4		39	μs
		10-bit resolution Target pin: Internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	3.6 V ≤ V_{DD} ≤ 5.5 V	2.375		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.8		39	μs
Zero-scale error[Notes 1, 2]	E_{ZS}	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±0.25	%FSR
Full-scale error[Notes 1, 2]	E_{FS}	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±0.25	%FSR
Integral linearity error[Note 1]	ILE	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±2.5	LSB
Differential linearity error[Note 1]	DLE	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±1.5	LSB
Analog input voltage	V_{AIN}	ANI2, ANI4 to ANI7		0		AV_{REFP}	V
		Internal reference voltage (HS (high-speed main) mode)		V_{BGR}[Note 4]			V
		Temperature sensor output voltage (HS (high-speed main) mode)		V_{TMPS25}[Note 4]			V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. When AV_{REFP} < V_{DD}, the MAX. values are as follows.

Overall error: Add ±1.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AV_{REFP} = V_{DD}.

Integral linearity error/Differential linearity error: Add ±0.5 LSB to the MAX. value when AV_{REFP} = V_{DD}.

4. See **3.6.2 Temperature sensor/internal reference voltage characteristics**.

(2) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target pin: ANI16 to ANI19

(T_A = –40 to +125°C, 2.7 V ≤ AV_{REFP} ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = AV_{REFP}, Reference voltage (–) = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error[Note 1]	AINL	10-bit resolution AV_{REFP} = V_{DD}[Note 3]			1.2	±5.0	LSB
Conversion time	t_{CONV}	10-bit resolution Target ANI pin : ANI16 to ANI19	3.6 V ≤ V_{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V_{DD} < 5.5 V	3.4		39	μs
Zero-scale error[Notes 1, 2]	E_{ZS}	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±0.35	%FSR
Full-scale error[Notes 1, 2]	E_{FS}	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±0.35	%FSR
Integral linearity error[Note 1]	ILE	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±3.5	LSB
Differential linearity error[Note 1]	DLE	10-bit resolution AV_{REFP} = V_{DD}[Note 3]				±2.0	LSB
Analog input voltage	V_{AIN}	ANI16 to ANI19		0		AV_{REFP} and V_{DD}	V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. When AV_{REFP} < V_{DD}, the MAX. values are as follows.

Overall error: Add ±4.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add ±0.2%FSR to the MAX. value when AV_{REFP} = V_{DD}.

Integral linearity error/Differential linearity error: Add ±2.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

(3) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (–) = V_{SS} (ADREFM = 0), target pin: ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19, internal reference voltage, and temperature sensor output voltage

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = V_{DD}, Reference voltage (–) = V_{SS})

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution			1.2	±7.0	LSB
Conversion time	t_{CONV}	10-bit resolution Target pin: ANI0 to ANI2, ANI4 to ANI7, ANI16 to ANI19	3.6 V ≤ V_{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.4		39	μs
Conversion time	t_{CONV}	10-bit resolution Target pin: Internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	3.6 V ≤ V_{DD} ≤ 5.5 V	2.375		39	μs
			2.7 V ≤ V_{DD} ≤ 5.5 V	3.8		39	μs
Zero-scale error Notes 1, 2	E_{ZS}	10-bit resolution				±0.60	%FSR
Full-scale error Notes 1, 2	E_{FS}	10-bit resolution				±0.60	%FSR
Integral linearity error Note 1	ILE	10-bit resolution				±4.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution				±2.0	LSB
Analog input voltage	V_{AIN}	ANI0 to ANI2, ANI4 to ANI7		0		V_{DD}	V
		ANI16 to ANI19		0		V_{DD}	V
		Internal reference voltage (HS (high-speed main) mode)		V_{BGR} Note 3			V
		Temperature sensor output voltage (HS (high-speed main) mode)		V_{TMPS25} Note 3			V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. See **3.6.2 Temperature sensor/internal reference voltage characteristics**.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target pin: ANI0, ANI2, ANI4 to ANI7, ANI16 to ANI19

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, Reference voltage (+) = V_{BGR} Note 3, Reference voltage (–) = AV_{REFM} Note 4 = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	RES		8			bit
Conversion time	t_{CONV}	8-bit resolution	17		39	μs
Zero-scale error Notes 1, 2	E_{ZS}	8-bit resolution			±0.60	%FSR
Integral linearity error Note 1	ILE	8-bit resolution			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution			±1.0	LSB
Analog input voltage	V_{AIN}		0		V_{BGR} Note 3	V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. See **3.6.2 Temperature sensor/internal reference voltage characteristics**.

4. When reference voltage (–) = V_{SS}, the MAX. values are as follows.

Zero-scale error: Add ±0.35%FSR to the MAX. value when reference voltage (–) = AV_{REFM}.

Integral linearity error: Add ±0.5 LSB to the MAX. value when reference voltage (–) = AV_{REFM}.

Differential linearity error: Add ±0.2 LSB to the MAX. value when reference voltage (–) = AV_{REFM}.

3.6.2 Temperature sensor/internal reference voltage characteristics

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V_{TMPS25}	Setting ADS register = 80H, T_A = +25°C		1.05		V
Internal reference voltage	V_{BGR}	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	F_{VTMPS}	Temperature sensor that depends on the temperature		–3.6		mV/C
Operation stabilization wait time	t_{AMP}		5			μs

3.6.3 Programmable gain amplifier

(T_A = –40 to +125°C, 2.7 V ≤ AV_{REFP} = V_{DD} ≤ 5.5 V, V_{SS} = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Input offset voltage	V_{IOPGA}					±5	±10	mV
Input voltage range	V_{IPGA}				0		0.9V_{DD}/gain	V
Gain error[Note 1]		4, 8 times					±1	%
		16 times					±1.5	%
		32 times					±2	%
Slew rate[Note 1]	SR_{RPGA}	Rising edge	4.0 V ≤ V_{DD} ≤ 5.5 V	4, 8 times	4			V/μs
				16, 32 times	1.4			V/μs
			2.7 V ≤ V_{DD} < 4.0 V	4, 8 times	1.8			V/μs
				16, 32 times	0.5			V/μs
	SR_{FPGA}	Falling edge	4.0 V ≤ V_{DD} ≤ 5.5 V	4, 8 times	3.2			V/μs
				16, 32 times	1.4			V/μs
			2.7 V ≤ V_{DD} < 4.0 V	4, 8 times	1.2			V/μs
				16, 32 times	0.5			V/μs
Operation stabilization wait time[Note 2]	t_{PGA}	4, 8 times			5			μs
		16, 32 times			10			μs

Notes 1. When V_{IPGA} = 0.1V_{DD}/gain to 0.9V_{DD}/gain.

2. Time required until a state is entered where the DC and AC specifications of the PGA are satisfied after the PGA operation has been enabled (PGAEN = 1).

Remark These characteristics apply when AV_{REFM} is selected as GND of the PGA by using the CVRVS1 bit.

3.6.4 Comparator

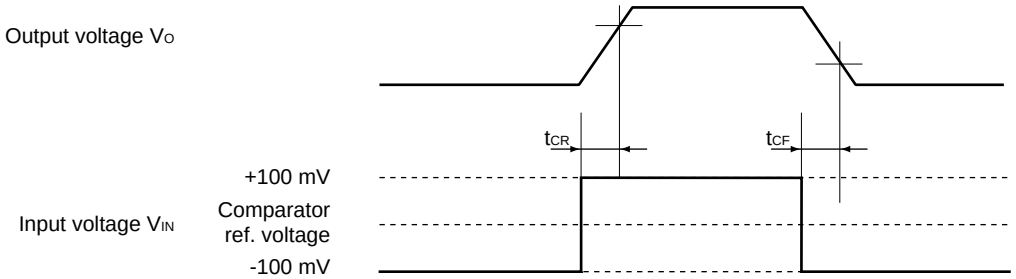
(T_A = –40 to +125°C, 2.7 V ≤ AV_{REFP} = V_{DD} ≤ 5.5 V, V_{SS} = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input offset voltage	V_{IOCMP}			±5	±40	mV
Input voltage range	V_{ICMP}	CMP0P to CMP5P	0		V_{DD}	V
		CMPCOM	0.045		0.9V_{DD}	V
Internal reference voltage deviation	ΔV_{IREF}	CmRVM register values: 7FH to 80H (m = 0 to 2)			±2	LSB
		Other than above			±1	LSB
Response time	t_{CR}, t_{CF}	Input amplitude = ±100 mV		70	150	ns
Operation stabilization wait time[Note 1]	t_{CMP}	3.3 V ≤ V_{DD} ≤ 5.5 V	1			μs
		2.7 V ≤ V_{DD} < 3.3 V	3			μs
Reference voltage stabilization wait time	t_{VR}	CVRE: 0 to 1[Note 2]	10			μs

Notes 1. Time required until a state is entered where the DC and AC specifications of the comparator are satisfied after the operation of the comparator has been enabled (CMPnEN bit = 1: n = 0 to 5)

2. Enable comparator output (CnOE bit = 1; n = 0 to 5) after enabling operation of the internal reference voltage generator (by setting the CVREm bit to 1; m = 0 to 2) and waiting for the operation stabilization time to elapse.

Remark These characteristics apply when AV_{REFP} is selected as the power supply source of the internal reference voltage by using the CVRVS0 bit, and when AV_{REFM} is selected as GND of the internal reference voltage by using the CVRVS1 bit.

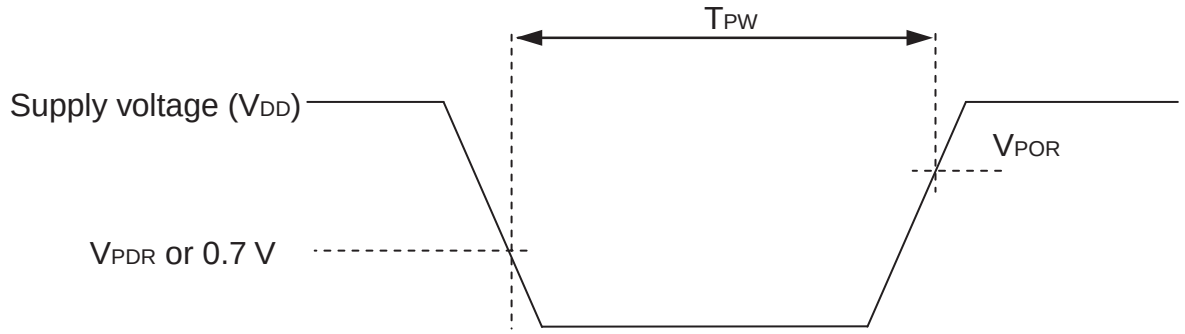


3.6.5 POR circuit characteristics

(T_A = –40 to +125°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V_{POR}	Power supply rise time	1.45	1.51	1.62	V
	V_{PDR}	Power supply fall time	1.44	1.50	1.61	V
Minimum pulse width[Note]	T_{PW}		300			μs

Note Minimum time required for a POR reset when V_{DD} exceeds below V_{PDR}. This is also the minimum time required for a POR reset from when V_{DD} exceeds below 0.7 V to when V_{DD} exceeds V_{POR} while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



3.6.6 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

(T_A = –40 to +125°C, $V_{PDR} \leq V_{DD} \leq$ 5.5 V, V_{SS} = 0 V)

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	Supply voltage level	V_{LVD0}	Power supply rise time	3.97	4.06	4.25	V
			Power supply fall time	3.89	3.98	4.15	V
		V_{LVD1}	Power supply rise time	3.67	3.75	3.93	V
			Power supply fall time	3.59	3.67	3.83	V
		V_{LVD2}	Power supply rise time	3.06	3.13	3.28	V
			Power supply fall time	2.99	3.06	3.20	V
		V_{LVD3}	Power supply rise time	2.95	3.02	3.17	V
			Power supply fall time	2.89	2.96	3.09	V
		V_{LVD4}	Power supply rise time	2.85	2.92	3.07	V
			Power supply fall time	2.79	2.86	2.99	V
		V_{LVD5}	Power supply rise time	2.75	2.81	2.95	V
			Power supply fall time	2.70	2.75	2.88	V
Minimum pulse width		t_{LW}		300			μs
Detection delay time						300	μs

LVD Detection Voltage of Interrupt & Reset Mode

(T_A = –40 to +125°C, $V_{PDR} \leq V_{DD} \leq$ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Interrupt and reset mode	V_{LVD0}	V_{POC2}, V_{POC1}, V_{POC0} = 0, 1, 1, falling reset voltage: 2.7 V		2.70	2.75	2.88	V
	V_{LVD1}	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.85	2.92	3.07	V
			Falling interrupt voltage	2.79	2.86	2.99	V
	V_{LVD2}	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.95	3.02	3.17	V
			Falling interrupt voltage	2.89	2.96	3.09	V
	V_{LVD3}	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.97	4.06	4.25	V
			Falling interrupt voltage	3.89	3.98	4.15	V

3.6.7 Supply voltage rise inclination characteristics

(T_A = –40 to +125°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Supply voltage rise	SV_{DD}				54	V/ms

Caution Keep the internal reset status by using the LVD circuit or an external reset signal until V_{DD} rises to within the operating voltage range shown in 33.4 AC Characteristics.

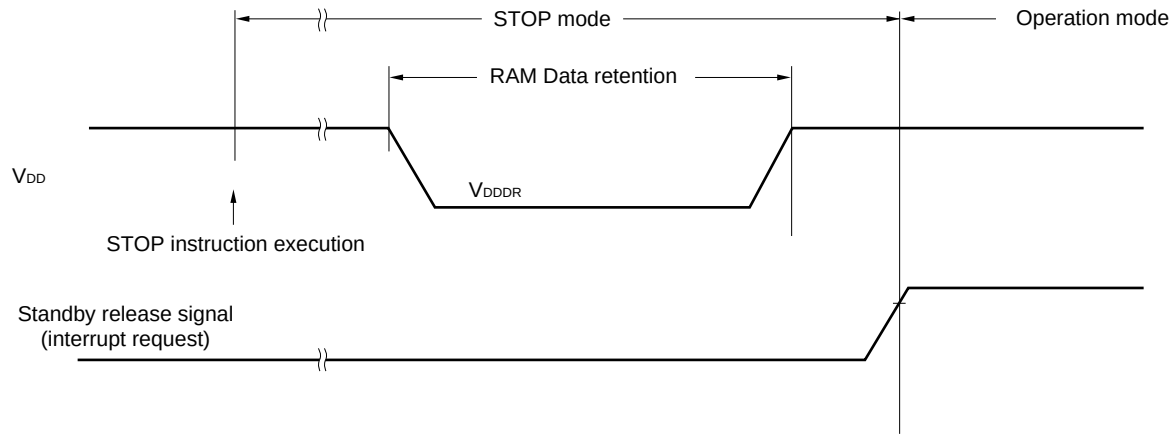
3.7 RAM Data Retention Characteristics

(T_A = –40 to +125°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage[Note 2]	V_{DDDR}		1.47[Note 1]		5.5	V

Note The value depends on the POR detection voltage. When the voltage drops, the RAM data is retained before a POR reset is effected, but RAM data is not retained when a POR reset is effected.

Caution When CPU is operated at the voltage of out of the operation voltage range, RAM data is not retained. Therefore, set STOP mode before the supplied voltage is below the operation voltage range.



3.8 Flash Memory Programming Characteristics

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	f_{CLK}	2.7 V ≤ V_{DD} ≤ 5.5 V	1		32	MHz
Number of code flash rewrites Notes 1, 2, 3	C_{erwr}	Retained for 20 years, T_A = 85°C Note 3, 4	1,000			Times
Number of data flash rewrites Notes 1, 2, 3		Retained for 1 year, T_A = 25°C Note 3, 4		1,000,000		
		Retained for 5 years, T_A = 85°C Note 3, 4	100,000			
		Retained for 20 years, T_A = 85°C Note 3, 4	10,000			

Notes
1. 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.
2. When using flash memory programmer and Renesas Electronics self programming library
3. These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.
4. These are the average temperature of during the retainment.

3.9 Dedicated Flash Memory Programmer Communication (UART)

(T_A = –40 to +105°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

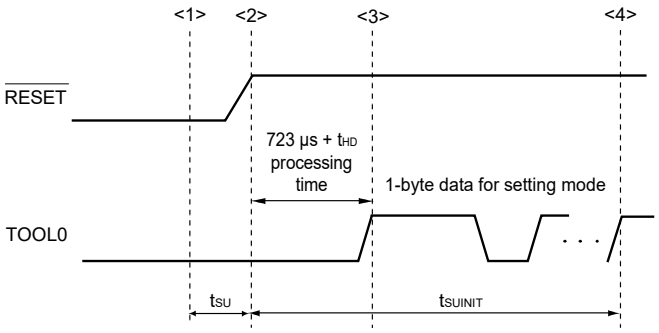
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115.2 k		1 M	bps

3.10 Timing of Entry to Flash Memory Programming Modes

(T_A = –40 to +125°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when an external reset ends until the initial communication settings are specified	t_{SUINIT}	POR and LVD reset must end before the external reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until an external reset ends	t_{SU}	POR and LVD reset must end before the external reset ends.	10			μs
How long the TOOL0 pin must be kept at the low level after a reset ends (except soft processing time)	t_{HD}	POR and LVD reset must end before the external reset ends.	1			ms

<R>



<1> The low level is input to the TOOL0 pin.
<2> The external reset ends (POR and LVD reset must end before the pin reset ends.).
<3> The TOOL0 pin is set to the high level.
<4> Complete the baud rate setting by UART reception.

Remark t_{SUINIT}: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.

t_{SU}: How long from when the TOOL0 pin is placed at the low level until an external reset ends

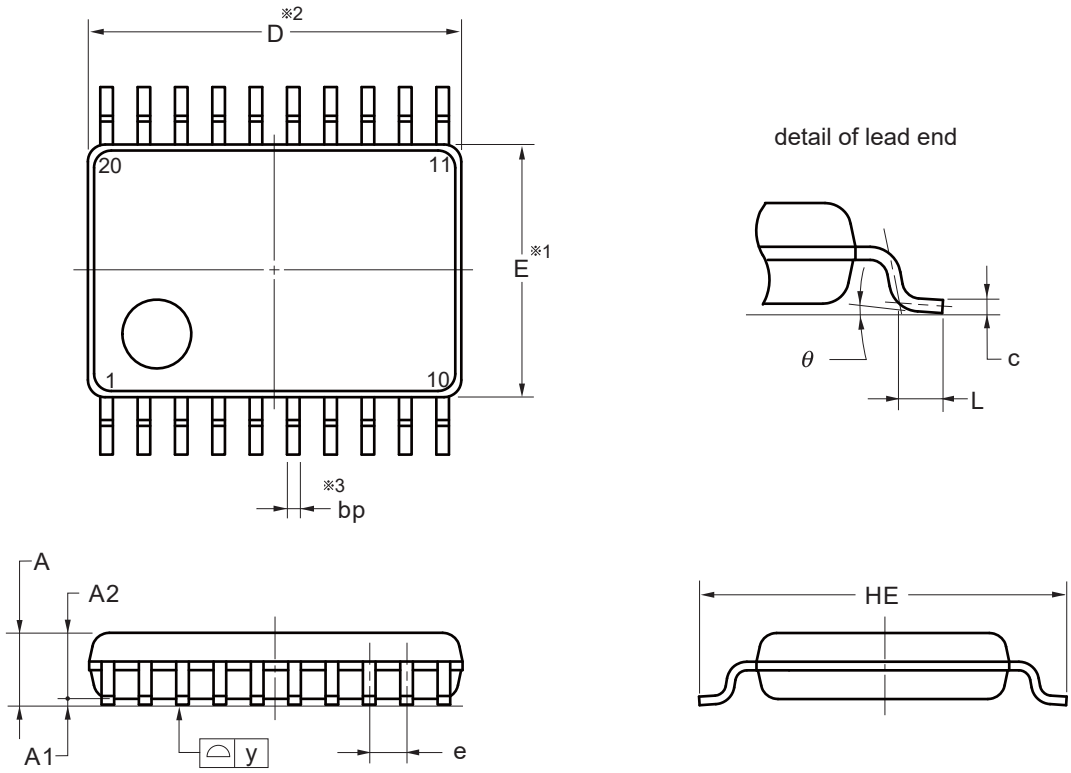
t_{HD}: How long to keep the TOOL0 pin at the low level from when the external and internal resets end (except soft processing time)

4. PACKAGE DRAWINGS

<R> 4.1 20-pin Products

R5F1076CGSP#V0, R5F1076CGSP#X0, R5F1076CMSP#V0, R5F1076CMSP#X0

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LSSOP20-4.4x6.5-0.65	PLSP0020JB-A	P20MA-65-NAA-1	0.1



(UNIT:mm)

ITEM	DIMENSIONS
D	6.50±0.10
E	4.40±0.10
HE	6.40±0.20
A	1.45 MAX.
A1	0.10±0.10
A2	1.15
e	0.65±0.12
bp	$0.22^{+0.10}_{-0.05}$
c	$0.15^{+0.05}_{-0.02}$
L	0.50±0.20
y	0.10
θ	0° to 10°

NOTE

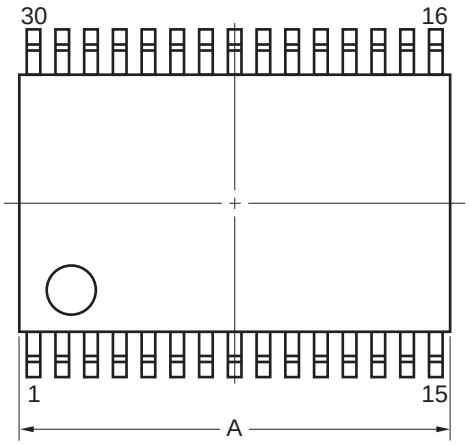
1.Dimensions "※1" and "※2" do not include mold flash.

2.Dimension "※3" does not include trim offset.

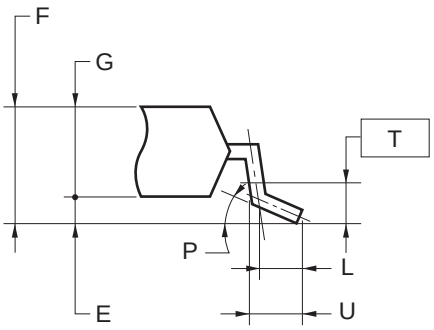
4.2 30-pin Products

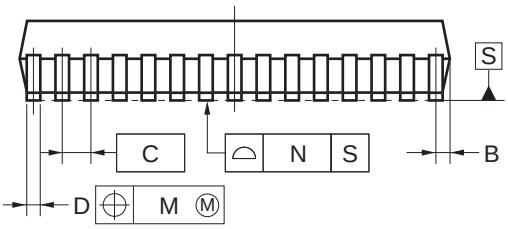
R5F107ACGSP#V0, R5F107AEGSP#V0, R5F107ACGSP#X0, R5F107AEGSP#X0, R5F107ACMSP#V0, R5F107AEMSP#V0, R5F107ACMSP#X0, R5F107AEMSP#X0

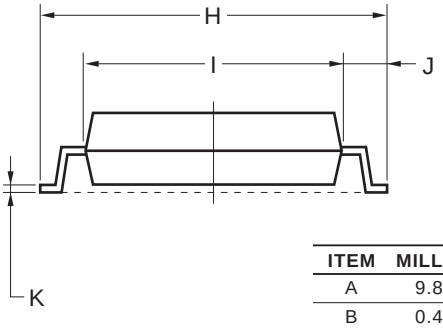
JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LSSOP30-0300-0.65	PLSP0030JB-B	S30MC-65-5A4-3	0.18



detail of lead end







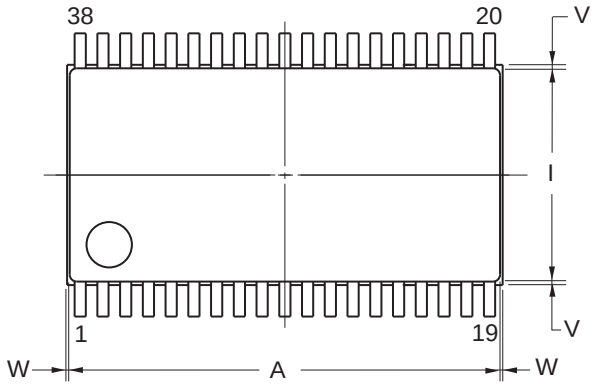
NOTE
Each lead centerline is located within 0.13 mm of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS
A	9.85±0.15
B	0.45 MAX.
C	0.65 (T.P.)
D	$0.24^{+0.08}_{-0.07}$
E	0.1±0.05
F	1.3±0.1
G	1.2
H	8.1±0.2
I	6.1±0.2
J	1.0±0.2
K	0.17±0.03
L	0.5
M	0.13
N	0.10
P	$3^{\circ}{}^{+5^{\circ}}_{-3^{\circ}}$
T	0.25
U	0.6±0.15

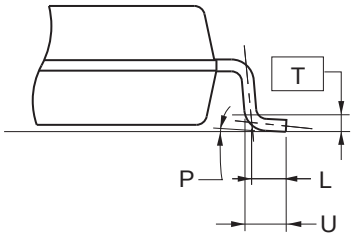
4.3 38-pin Products

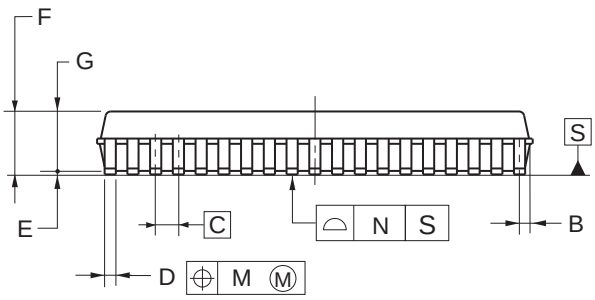
R5F107DEGSP#V0, R5F107DEGSP#X0, R5F107DEMSP#V0, R5F107DEMSP#X0

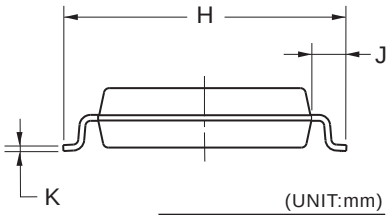
JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-SSOP38-0300-0.65	PRSP0038JA-A	P38MC-65-2A4-2	0.3



detail of lead end







(UNIT:mm)

ITEM	DIMENSIONS
A	12.30±0.10
B	0.30
C	0.65 (T.P.)
D	$0.32^{+0.08}_{-0.07}$
E	0.125±0.075
F	2.00 MAX.
G	1.70±0.10
H	8.10±0.20
I	6.10±0.10
J	1.00±0.20
K	$0.17^{+0.08}_{-0.07}$
L	0.50
M	0.10
N	0.10
P	$3^{\circ}{}^{+7^{\circ}}_{-3^{\circ}}$
T	0.25(T.P.)
U	0.60±0.15
V	0.25 MAX.
W	0.15 MAX.

NOTE

Each lead centerline is located within 0.10 mm of its true position (T.P.) at maximum material condition.

Rev.	Date	Description	
		Page	Summary
3.20	Sep 29, 2017	p.1	Modification of description in 1.1 Features
		p.59	Modification of figure in 2.10 Timing of Entry to Flash Memory Programming Modes
		p.102	Modification of figure in 3.10 Timing of Entry to Flash Memory Programming Modes
		p.103	Modification of figure in 4.1 20-pin Products

NOTES FOR CMOS DEVICES

(1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).

(2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.

(3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.

(4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.

(5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.

(6) INPUT OF SIGNAL DURING POWER OFF STATE : Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

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